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A Semiautomatic AC/DC Thermal Voltage Converter Calibration System

U.S. DEPARTMENT OF COMMERCE National Bureau of Standards National Engineering Laboratory Center for Electronics and Electrical Engineering Electrosystems Division Washington, DC 20234

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Final Report

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K. J. Lentner, S. G. Tremaine

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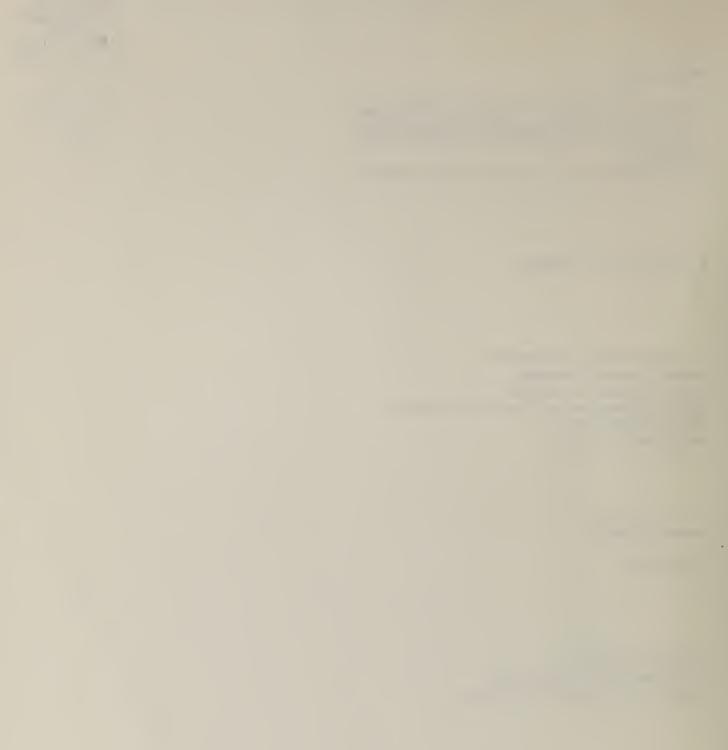
Final Report

Sponsored in part by: U.S. Department of Defense Calibration Coordination Group



U.S. DEPARTMENT OF COMMERCE, Malcolm Baldrige, Secretary NATIONAL BUREAU OF STANDARDS, Ernest Ambler, Director

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FOREWORD

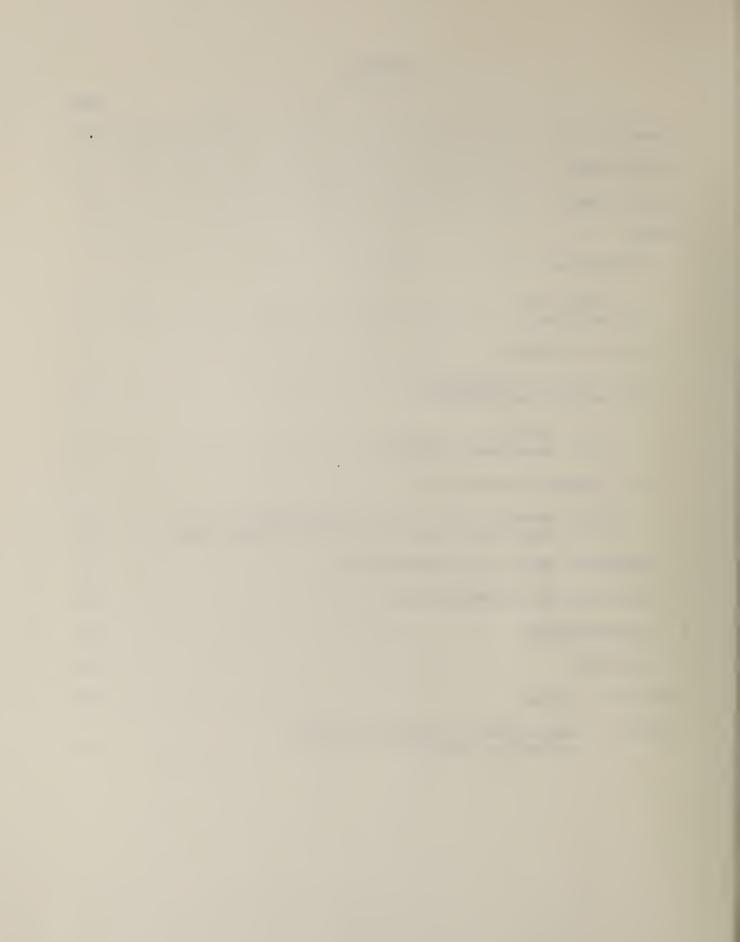
The development of the system described in this report was partially funded by the U.S. Department of Defense Calibration Coordination Group (DoD/CCG). Members of the DC and LF Committee were from the Aerospace Guidance and Metrology Center, Newark Air Force Station, Newark, Ohio 43055; the U.S. Army Metrology and Calibration Center, Redstone Arsenal, Huntsville, Alabama 35809; and the Metrology Engineering Center, Bureau of Naval Weapons Representative, Pomona, California 91766.

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In order to adequately describe the system discussed in this report, commercial equipment and instruments are identified by manufacturer's name and model number. In no case does such identification imply recommendation or endorsement by the National Bureau of Standards, nor does it imply that the material or equipment identified is necessarily the best available for the purpose.

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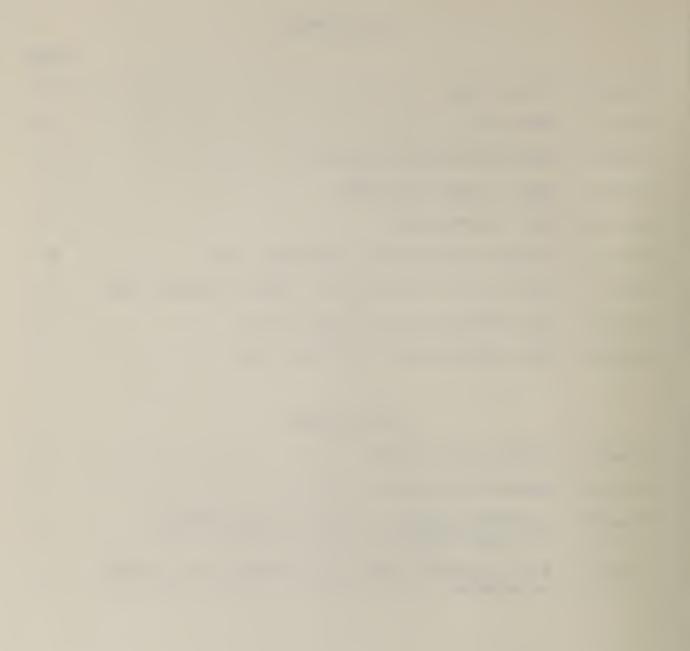


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A SEMIAUTOMATIC AC/DC THERMAL VOLTAGE CONVERTER CALIBRATION SYSTEM

K. J. Lentner and S. G. Tremaine

Abstract

A semiautomatic ac/dc difference calibration system is described. The system operates over a frequency range of 20 Hz to 100 kHz, covering the voltage range from 0.5 V to 1 kV. For all voltages at frequencies in the range from 20 Hz to 20 kHz, the total uncertainty is 50 parts per million (ppm), and 100 ppm for voltages at frequencies between 20 kHz and 100 kHz. In addition to ac/dc difference testing, the system can be readily adapted to calibrate precision ac digital voltmeters or ac calibrators. Results of extensive intercomparison testing of the new system against a manual test system are reported, using a multirange thermal transfer instrument as a transport standard. The results indicate that the ac/dc differences measured are well within the combined total uncertainty limits of the two systems.

Key words: ac/dc difference; ac voltage measurement; automation; calibration; metrology; thermal voltage converter.

1. INTRODUCTION

1.1 Objectives

The Semiautomatic AC/DC Thermal Voltage Converter Calibration System, developed at the National Bureau of Standards and described in this report, was designed to use electronic technology to overcome the deficiencies of existing manual test methods. Specific objectives for the new system included: 1) use of commercially available, programmable instruments whenever possible; 2) elimination of the need for manual data entry into a computer for reduction; 3) elimination of the frequent data checks and cross-checks required in manual tests; 4) elimination of as much operator intervention as possible during the test procedure; 5) simplification of necessary remaining interaction by providing displayed operator instruction via computer control; 6) close control of the time interval between application of both ac and dc voltages to the test circuit in order to minimize drift effects; and 7) achievement of the same level of uncertainty as is presently possible with manual testing methods.

1.2 Background

Techniques for performing precision ac/dc difference testing, not only at the National Bureau of Standards (NBS), but also in other national and industrial or governmental metrology laboratories, generally make use of manual testing methods which utilize photocell preamplifiers and lightbeam galvanometers as voltage detectors in conjunction with manually balanced voltage comparators [1,2].¹ Careful attention to the elimination or reduction of systematic and random uncertainties in testing methods, range resistors, and thermoelements (TE's) has resulted in sufficient confidence in test data to allow results to be reported with total uncertainties at the 10-100 ppm level (or better, in some cases) over wide voltage and frequency ranges [3,4]. These manual test methods, however, are very time-consuming and subject to errors due to operator fatigue. To overcome these deficiencies, and to expedite test report generation, a semiautomatic ac/dc calibration system was developed.

Because of the low-level dc voltages that must be measured (about 10 nV), large temperature coefficients of TE's, ac or dc source instabilities, and dc reversal differences of TE's, stringent requirements are placed upon the measurement system. In addition, light beam galvanometers suffer the disadvantage of not being easily adaptable to automation. However, with the advent of digital electronics, digital nanovoltmeters are available with sensitivity, resolution, and accuracy sufficient to meet the requirements of precision automatic ac/dc difference testing. Programmable ac and dc voltage calibrators are also available which lend themselves to adaption for automatic testing. Advances in analog/digital interfaces have greatly improved the ease with which computers can be used to control these instruments. The semiautomatic system which evolved is shown in figure 1, and is described in detail in this report. The system operates over a frequency range of 20 Hz to 100 kHz, covering the voltage range from 0.5 V to 1 kV. For all voltages at frequencies in the range from 20 Hz to 20 kHz, the total uncertainty is 50 ppm, and 100 ppm for all voltages at frequencies between 20 kHz and 100 kHz. In addition to ac/dc difference testing, the system can be readily adapted to calibrating precision ac digital voltmeters or ac calibrators. Extensive testing of the new system using a multirange thermal transfer instrument as a transport standard indicates that the test results are well within the reported uncertainty limits. In addition, data obtained with the system indicate that total random uncertainties (3 Jimits) of about 3 ppm can be obtained for some ac/dc difference tests.

2. TECHNICAL APPROACH

2.1 Principle of Operation

A block diagram of the semiautomatic system is shown in figure 2. In principle, the system is similar to the manual system presently used at NBS for routine calibration work, except that overall system control and data acquisition and processing are provided by a 16-bit minicomputer. Programmable ac and dc standards supply the voltages to the thermal converters (consisting of the TE and various range resistors). Such voltage standards are often referred to as ac or dc calibrators. The output voltages of the two converters (as well as the difference between the two voltages) are measured in a semiautomatic mode by means of a

Numbers in brackets refer to the literature references listed at the end of this report.

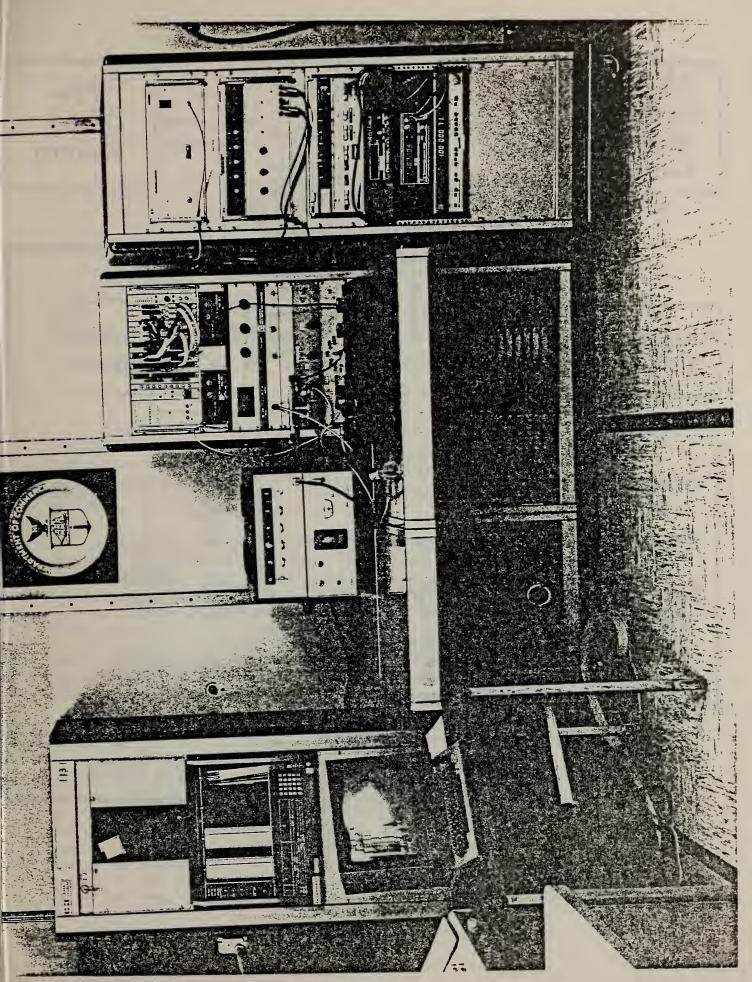


Figure 1. Overall view of system

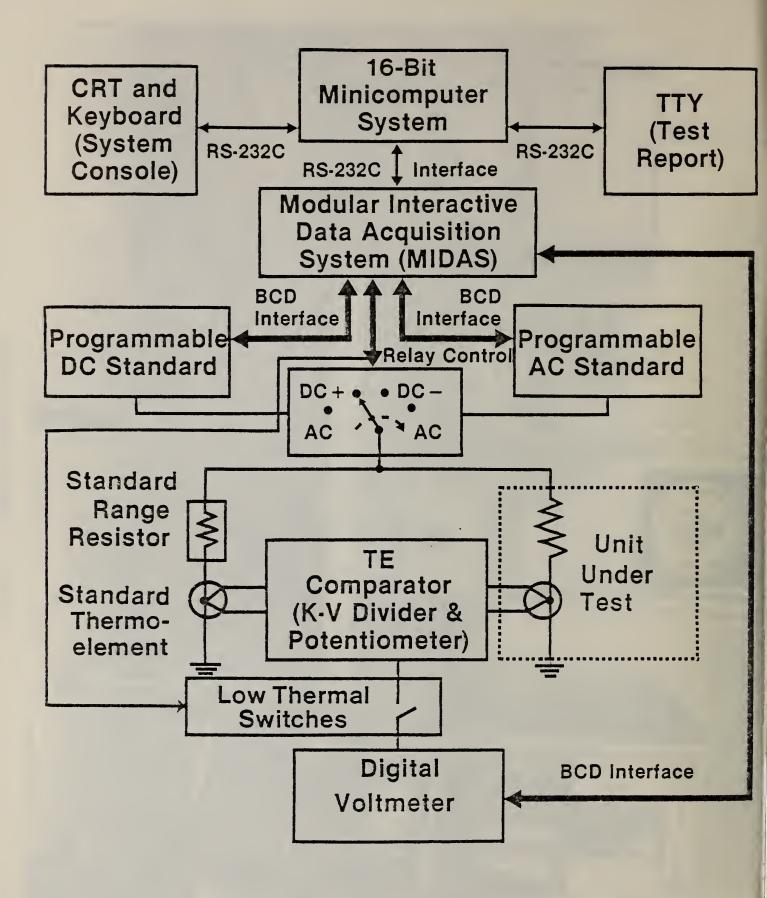


Figure 2. System block diagram

manually operated TE comparator and a digital voltmeter which is automatically controlled via the computer. The computer, its peripheral equipment, and the Modular Interactive Data Acquisition System (MIDAS) [5] are interconnected utilizing the standard RS-232C interface. The programmable instruments and the high voltage and low-thermal-noise switches are controlled by the computer via the MIDAS digital interface.

In operation, the ac or dc voltages are applied simultaneously to the standard TE and the unit under test (UUT). The difference in the output voltages is primarily balanced out by the TE comparator. The small residual differences in the TE output voltages are automatically measured with the digital voltmeter as the inputs are switched between the ac and dc voltages. Typically, the voltage differences are manually balanced to less than 100 nV. The residual voltages are then measured with a resolution of 10 nV, requiring a voltmeter with only moderate accuracy but with low noise. In addition, the voltmeter is used to measure the nominal output voltages of both converters.

2.2 Hardware Considerations

2.2.1 General

As mentioned previously, the components of the semiautomatic system (except for the computer, its peripheral equipment, and interfaces) are similar to manual systems used at NBS. The principle differences for the new system are the use of a sensitive digital voltmeter and programmable dc and ac voltage standards. A listing of the hardware contained in the system is provided in appendix A.

Overall system control is provided by means of a 16-bit minicomputer which has 64 kbytes of core memory and a dual floppy-disk unit for program and data storage. The system console (CRT), the teletypewriter (TTY), and MIDAS are connected to the computer by means of interfaces which conform to the EIA RS-232-C standard [6]. MIDAS hardware is based on the CAMAC standard [7] and consists of several functional modules which are inserted into slots in an equipment rack. A power supply and MIDAS controller module also are required to make the MIDAS system operational. Communication between the controller module and individual MIDAS modules is in accordance with the ASCII standard code for information interchange [8].

The dc and ac voltage standards must have wide voltage and frequency ranges to meet the requirements of calibration work for which the system is intended. In addition, the standards must be stable and have sufficient resolution to permit precision measurements to be made. The dc voltage standard has ranges of 10 V, 100 V, and 1 kV with resolutions of 1 μ V, 10 μ V, and 100 μ V per step, respectively, with ten steps per range. The specified accuracy is about 30 ppm of range for all three ranges, with output stability of about 15 ppm of programmed output per month. The ac voltage standard has seven decade ranges covering the voltages from 1 mV to 1 kV (full-scale ranges) with a resolution of 10 ppm of range per step, with ten steps per range.

of eleven fixed frequencies per range, covering the range 10 Hz to 110 kHz, with frequency range multipliers of X10 Hz and X100 Hz, X1 kHz and X10 kHz. The accuracy of the ac standard's voltage output varies with frequency, from about 0.02% to 0.05% of voltage setting. The voltage stability is specified as 0.01% of setting for six months.

The digital voltmeter has eight ranges from $\pm 10 \mu V$ to $\pm 100 V$. On the most sensitive $10 \mu V$ range, it has a resolution of 10 nV, with an input impedance of about $10 M_{\Omega}$. The zero stability is specified as less than 100 nV per hour. In the frequency range dc to about 10 Hz, the voltmeter has less than 50 nV of rms noise, referred to the input, with the input shorted.

It should be noted that two digital panel meters used to monitor the outputs of the voltage standards, as well as a frequency counter used to monitor the ac frequency, are not included in figure 2 (for simplicity), but they are visible in figure 1. The large instrument on the left of the test console table (fig. 1) is an ac calibrator under test.

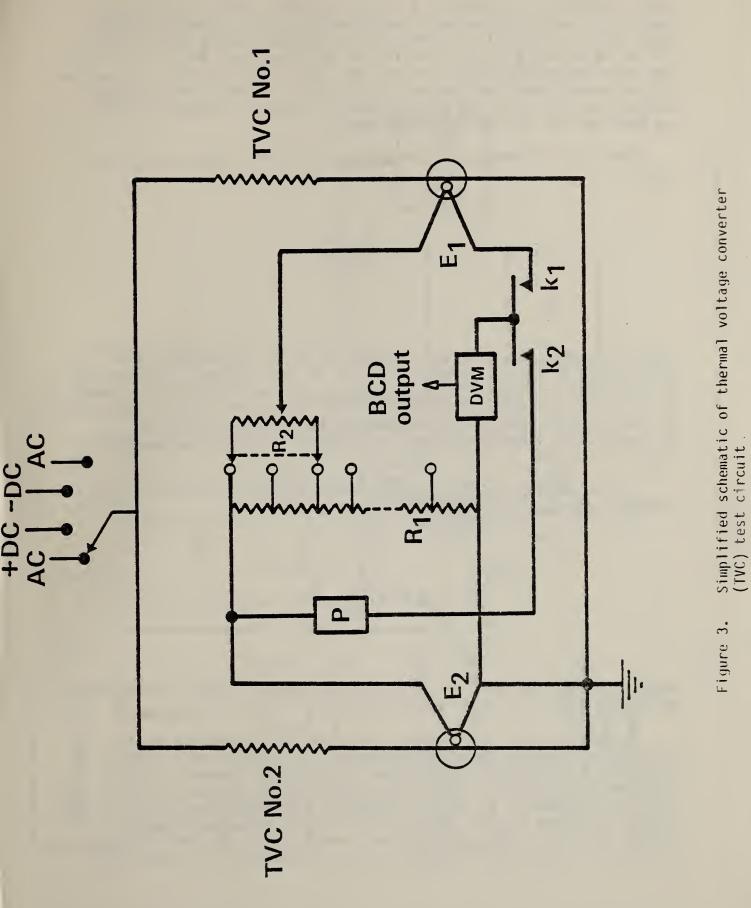
A critical problem in making nanovolt measurements is that of obtaining switches which have low-thermal-noise, and can be controlled automatically. Ideally, TE output voltages of about 10 mV should be measured to within 1 ppm (10 nV). Mercury-wetted contact, self-latching, solid-state and reed relays were found to be unsuitable since these types have thermal-noise on the order of 1μ V. The problem was solved by modifying manually operated low-thermal-noise switches. Solenoids with 24-V operating coils were mechanically linked to such switches. The operating coils are energized by programmable MIDAS relays which connect the 24-V supply to the coils.

The switches which apply the ac or dc voltages to the test circuit are electro-mechanical relays capable of switching up to 5 kV. The 24-V operating coils of these relays also are controlled by MIDAS relays.

2.2.2 Measurement Procedures

The various measurement steps will now be explained in some detail for the determination of ac/dc difference, and for determination of the corrections to the nominal output voltages of an ac voltage standard.

A portion of the circuit for ac/dc difference testing, including the components of the TE comparator, is shown in figure 3. The thermal voltage converter (TVC) No. 2 can be either the standard or test converter. The only requirement is that E_2 must be greater that E_1 and, for purposes of this discussion, it is assumed that the test TVC is in the No. 2 position. With rated dc voltage applied, and with the potentiometer (P) turned off, the emf outputs (E_2 of the test unit, E_1 of the standard) are measured by the digital voltmeter (DVM) with switch K2 closed. Another switch in the TE comparator (not shown in fig. 3) permits



manual selection of either the E_2 or E_1 voltages. With the voltmeter reading E_2 , the potentiometer is adjusted until the voltmeter indicates about 500 nV. Switch K2 is opened, K1 is closed, and the Kelvin-Varley divider is adjusted until the voltmeter indicates about 100 nV. The test then proceeds automatically, and ac, dc+, dc-, and ac voltages are applied (in the order listed) to the test circuit [2]. The difference voltages between the outputs of the test and standard thermal voltage converters are measured for all four input voltages.

The ac/dc difference, in ppm, for the unit under test, as derived in [2], is

$$\delta_t = \delta_s + \frac{E_d - E_a}{n_s E_s},$$

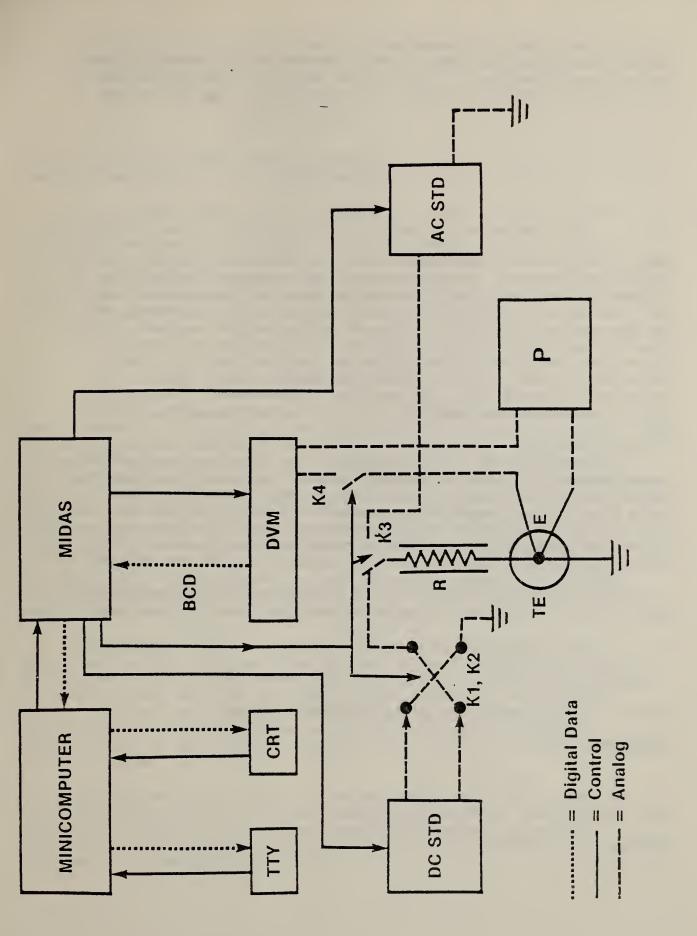
where δ_S is the correction to the standard, E_d is the average emf of the standard TE with two directions of dc voltage applied, E_a is the emf of the standard TE with ac voltage applied, n_s is a dimensionless factor (≤ 2) of the standard, and E_s is the output emf of the standard TE at rated dc voltage input. If $E_d - E_a$ is measured in nanovolts, and E_s in millivolts, the expression for δ_t is conveniently given in ppm, provided that δ_s is in ppm.

If the standard TE has a higher output emf than the test TE, the previous expression is modified to become

$$\delta_t = \delta_s + \frac{E_d - E_a}{n_s E_t},$$

where all terms and units are as previously defined, and E_t is the output emf of the test TE at rated dc voltage input.

A block diagram of the system when used for calibrating an ac standard or voltmeter is shown in figure 4. As shown in this figure, the system's ac standard is connected for testing. However, the UUT, indicated as "AC STD," could as well be an external ac standard or a precision voltmeter. Kl and K2 are the dc+ and dc- high voltage switching relays, K3 is the ac high voltage relay, and K4 is a low-thermal-noise switch. Using this test circuit, the corrections to the nominal output voltage (at a given dial setting) of an ac standard can be determined



Block diagram of system for calibrating an ac standard or voltmeter Figure 4.

9

by using the system's programmable dc voltage standard (set to the same nominal value as the ac standard) and a thermal voltage converter, both having known corrections. For this case, only the Lindeck potentiometer (P) of the TE comparator is used. The correction to the UUT, in ppm, is

$$C_{t} = \delta_{s} + \frac{E_{a} - E_{d}}{nE} + C_{dc},$$

where δ_S is the ac/dc difference correction (in ppm) of the TVC at the test frequency, E_a is the reading of the voltmeter (DVM) with ac voltage applied (i.e., the difference between the TE's output emf and the fixed voltage of the Lindeck potentiometer), E_d is the average of the DVM readings with direct voltage of both polarities applied, n is a dimensionless factor equal to 2 if the TE has a square-law response, E is the TE's output emf at the applied test voltage, and C_{dc} is the correction (in ppm) to the dc voltage standard's nominal output. As for ac/dc difference tests, the equation is conveniently given in ppm if $E_a - E_d$ is in nanovolts and E is in millivolts, with δ_S and C_{dc} also in ppm.

The denominator of the correction equation contains the dimensionless characteristic "n." Most TE's do not have an ideal square-law response, hence, the value of n must be determined. Since n generally ranges in value from 1.6 to 2, neglecting to measure a TE's actual value of n can lead to significant errors in the correction to the UUT. For example, in the worst case, if n is assumed to be 2, but actually is 1.6, then the error amounts to (2-1.6)/(2) = 0.2, or 20 percent of the correction.

The procedure for measuring n (to a first order of approximation) is based on the fact that a TE's output voltage (E) can be expressed as

 $E = kI^n$,

where I is the current through the TE's heater element.

Therefore,

and

$$dE = knI dI$$
,

$$dE/E = (knI''' dI)/(kI'')$$

dE/E = n(dI/I),

Hence,

and, assuming constant heater resistance and a stable voltage source,

$$dE/E \simeq n(dV/V)$$
,

where V is the dc voltage applied across the series combination of a range resistor and a TE.

Two techniques can be used to measure the characteristic n. One involves making small, accurately known changes in the voltage (ΔV). The second involves making changes in the TE's heater current (I) with the applied voltage held constant. In the second method, which is used for the MIDAS-based system, small changes in the heater current through the TE under test are obtained when a 400 Ω resistor, in series with a 40 k Ω range resistor, is shorted by closing a MIDAS relay.

2.3 Software Considerations

2.3.1 General

In order to reduce the effort involved in making routine tests, the software for the system was designed to provide as much interaction between the system console and the operator as possible. This interaction is used to reduce the possibility of damage to either the standard or UUT when either software or hardware failures occur. Also, by progressing logically through the initialization portions of the test routines, the operator, when necessary, can take whatever corrective actions might be required. A significant advantage of the resulting software design is that sufficient warm-up time is automatically provided between application of the various test voltages so that the effects of errors due to the warm-up drifts of the standard and test units are reduced. In addition, the computer closely controls the time intervals between voltmeter readings; hence, the effects of linear drift are minimized.

The programs, which are written in BASIC, provide the means for automatically setting the ac or dc voltages and ac frequency, operating the voltage relays and low-thermal-noise switches, triggering the voltmeter to obtain voltage readings, and storing these readings in the computer memory. Six programs constitute the major testing software package. Program ACDCLV is used for making ac/dc difference tests at voltages from 0.5 to 95 V, and ACDCHV is used for similar tests at voltages greater than 105 V up to 1 kV.

Since the major application of the work described in this report is ac/dc difference testing, a typical sequence of operations for this type of testing is described below where the ACDCHV program is discussed. The other five programs will only be mentioned briefly; however, detailed information is available upon request. ACDCHV is a program which provides partial automatic control of ac/dc difference testing at voltages greater than 105 V. Since the MIDAS interface does not have isolated analog and digital grounds, it was necessary to develop a separate software package for high-voltage testing. At high voltages, it was found that operating either the ac or dc voltage relays introduced transient voltage surges into the MIDAS digital circuitry. The MIDAS controller interpreted these surges as voltage level changes identical to programmed commands. The result was that incorrect relays might be opened or closed, the voltmeter might be falsely triggered to obtain a reading, or any other of a series of unwanted events might occur. Hence, the ACDCHV program was developed to ensure that no high-voltage standards are turned on whenever a voltage relay is operated. To avoid unnecessary operation of the high-voltage relays, program ACDCLV should be used for tests below 100 V.

Basically, ACDCHV contains three general sections. At the beginning, test documentation (e.g., date, test number, observer, and instrument) is requested. String and array variables are dimensioned, and various simple variables are initialized. A heading for the test documentation is created by the operator. The midsection includes a network of subroutines that interact with the operator. Displayed instructions prompt the operator to define test parameters for setting ac and dc voltages, to switch the TE comparator from E-high to E-low, and to initially balance the Kelvin-Varley divider and rebalance it when necessary. Repeatedly accessed subroutines close and open the appropriate relays, set the input voltages, determine the TE emf output voltages, trigger the voltmeter to read the TE difference voltages, and calculate the ac/dc difference of the UUT for four determinations at each test point. Finally, statistical calculations are performed and the results are printed on the TTY. Options are then provided for the operator to choose whether to stop, repeat a test with or without averaging, or change parameters and run another test.

Program NTSTF is used to determine a TE's dimensionless factor, n [1,2]. The variation of n as a function of a TE's heater current can be expressed as $n \approx g$ (E), and this function is assumed to vary linearly. The program automatically fits a least-squares line to the data. The computational techniques used are fully discussed on pages 5-10 of [10]. Typical test results are illustrated in table 1.

Table 1. N-Test-F data

DATE .		THUR. 29	MARCH 79	9		OBSERVER	кJL	
TEST NO)	N-TEST		INST NO.	FA			
VOLTS	Е		١	4		AVE.N	NE	500/N
100	2.70	(1.992	1.991	1.990	1.990)	1.991	5.37	251.2
100	2.70	(1.988	1.988	1.989	1.991)	1.990	5.37	251.3
120	3.88	(1.973	1.973	1.974	1.975)	1.974	7.66	253.3
120	3.88	(1.973	1.974	1.975	1.975)	1.974	7.66	253.3
140	5.24	(1.954	1.955	1.956	1.956)	1.955	10.25	255.7
140	5.24	(1.954	1.955	1.957	1.956)	1.955	10.25	255.7
160	6.79	(1.922	1.923	1.925	1.923)	1.923	13.06	260.0
160	6.79	(1.922	1.923	1.924	1.923)	1.923	13.06	260.0
180	8.50	(1.881	1.881	1.883	1.882)	1.882	16.00	265.7
180	8.50	(1.878	1.881	1.883	1.882)	1.881	15.99	265.8
200	10.34	(1.833	1.833	1.835	1.833)	1.833	18.96	272.7
200	10.34	(1.826	1.832	1.834	1.834)	1.833	18.95	272.8

THE CURVE FITTING PROCESS USES A LEAST-SQUARES FIT FOR A POLYNOMIAL OF DEGREE ONE. THE N (LOWER CASE) TE CHARACTERISTIC (Y-AXIS) VERSUS TE EMF (X-AXIS) IS ASSUMED TO BE A LINEAR FUNCTION OF THE FORM Y = B+MX OR, IN THIS CASE:

NI = M - NEWHERE NI = TE CHARACTERISTIC M = ZERO X INTERCEPTN = NEGATIVE OF CURVE SLOPE E = TE OUTPUT EMF. . . . 2.05518206568E-1 N = . .

M = .

13

ACCAL is a program used to calibrate an ac voltage standard, a precision ac digital voltmeter, or the ac standard of the system in terms of a thermal voltage converter and the system's calibrated dc standard, as discussed in the previous section. Results for the calibration of an ac voltage standard are illustrated in table 2. The last column, "T CORR PPM," shows the correction to the calibrator's nominal output voltage.

Stability of the system's dc and ac standards can be checked by using programs called STABLV and STABHV. These progams are used for voltage ranges similar to those for ACDCLV and ACDCHV. Occasionally, test results appear to be erratic. These stability tests are useful in determining if the supplies are functioning properly. Stability of the sources is measured by using a programmable 6-1/2 digit multimeter whose function, ranges, and reading rates are remotely controlled. Initial stability test parameters for voltage, frequency, time between readings, and total number of readings are defined by the operator. The program then exercises automatic control over the ac and dc standards, the voltage relays, and the voltmeter. At completion, stability data including the values of minimum, maximum, range, average, standard deviation of the mean, and three times the standard deviation of the mean (calculated 3 limits) for both ac and dc voltage readings are printed on the TTY. Table 3 shows the results of a test at 95 V, 50 kHz, with the voltmeter programmed to use a 10-second integration time. The total time for the test illustrated was about 12 minutes, which is about the time it takes to do a test run (i.e., four determinations) for ac/dc difference tests at one frequency and voltage.

The advantages of the stability tests are illustrated in table 4. The difference in the ranges of the ac voltage for tests at 95 V and 200 V indicates that the ac high-voltage amplifier had become unstable. The instability was verified by a 12-minute test in which the ac voltage range was about 1150 ppm at 20 V as opposed to about 347 ppm at 95 V.

In addition to the test capabilities discussed above, the methodology and computer programs were developed for testing one model of a precision multirange automatic thermal transfer instrument as a voltmeter. Detailed information is available and can be supplied upon request.

2.3.2 Operating Procedure for AC/DC Difference Tests

For the reader not interested in the operational details of this program (contained in appendix B), the following overview is provided. The specific operating procedures include the following steps and instructions:

 Input via the system console, the test number, voltage, frequency, observer's name, and code for the standard thermal converter.

2) Visually check to see that both software and hardware are operating correctly by checking the system's digital panel meters and frequency meter for correct readings of the outputs from the ac and dc standards. If the outputs are incorrect, repeat step 1.

Table 2. ACCAL data

DATE			0	BSER	VER					
TEST	NO .	• • • • •	I	NST.	•••	• • • •	• • •	••••	•	
KHZ	CORR PPM	٧	TE RAN	ST	STANDA TE	ARD RANGE	E MV	NE		T CORR PPM
		100.0	10	0.0	FB	100.0	10.4	18.6		
0.8	0		(7	8	7	10)			-8	-8
0.8	0		(7	6	7	3)			- 7	-7
0.8	0		(7	8	8	3)			-7	-7
0.8	0		(5	1	4	3)			-6	- 6
2.4	0		(29	32	33	33)			32	32
2.4	0		(30	35	34	3 5)			33	33
2.4	0		(32	35	25	38)			33	33
2.4	0		(31	31	32	35)			33	33
4.8	0		(278	282	281	284)			281	281
4.8	0		(278	284	284	283)			282	282
4.8	0		(278	284	284	285)			282	282
4.8	0		(281	283	285	283)			283	283
0.4	0		(11	13	10	9)			11	11
0.4	0		(3	8	9	8)			8	8
0.4	0		(5	8	9	9)			8	8
0.4	0		(5	9	11	8)			8	8

Table 3. Low voltage stability test data

		J		
READING	DC-VOLTAGE	E PPM	AC-VOLTAGE	PPM
NO. 1	95.00530	55.9	****	****
NO. 1 (A)	****	****	94.51200	-5136.9
NO. 2	95.00530	55.9	****	****
NO. 2 (A)	****	****	94.51300	-5126.3
NO. 3	95.00530	55.9	****	****
NO. 3 (A)	****	****	94.51200	-5136.9
NO. 4	95.00540	56.5	****	****
NO. 4 (A)	****	****	94.51200	-5136.9
NO. 5	95.00530	55.9	****	****
NO. 5 (A)	****	****	94.51200	-5136.9
NO. 6	95.00530	55.9	****	****
NO. 6 (A)	****	****	94.51100	-5147.4
NO. 7	95.00510	54.0	****	****
NO. 7 (A)	****	****	94.51000	-5158.0
NO. 8	95.00510	54.0	****	****
NO. 8 (A)	****	****	94.50800	-5179.0
NO. 9	95.00520	54.6	****	****
NO. 9 (A)	****	****	94.50700	-5189.4
NO. 10	95.00510	54.0	****	****
NO. 10 (A)	****	****	94.50700	-5189.4
DC				
DC NO. OF	MEAN	STAN. DEV.	STAN. DEV.	STAN. DEV.
READINGS	(PPM)	OBSERVATION	MEAN	MEAN *3
10	55.3	1.0	0.3	1.0
MIN = 53.9679	9 MAX = 5	56.5378	RANGE = 2 .	5699
AC				
NO. OF		STAN. DEV.		
READINGS		OBSERVATION	MEAN	MEAN *3
	-5153.7			22.6
	3 MAX = -		RANGE = 63	.1211
V-NOMINAL 95	FREQUENCY 50 kHz	INT. TIME 10 SEC	TIME DELAY 10	
	00 KHZ			

•

Table 4. Stability test data summary Program: STABLV - Overnight (17 hr) Test DC No. of Stan. Dev. Stan. Dev. Mean Stan. Dev. Readings (PPM) Observation Mean Mean *3 50 42.1 5.0 0.7 2.1 Min = 36.7817Max = 56.5378Range = 19.7561 AC No. of Mean Stan. Dev. Stan. Dev. Stan. Dev. Readings (PPM) Observation Mean Mean *3 216.6 7.2 50 51.0 21.6 Max = 431.583Min = 84.1643Range = 347.419Int. Time V-Nominal Frequency Time Delay 95 1 kHz 10 sec 57500 Program: STABHV - Overnight (17 hr) Test DC No. of Stan. Dev. Mean Stan. Dev. Stan. Dev. Observation Mean Mean *3 Readings (PPM) 0.4 2.7 50 17.1 1.1 Min = 9.99451Max = 19.989Range = 9.99451AC No. of Mean (PPM) Stan. Dev. Stan. Dev. Stan. Dev. Observation Readings Mean Mean *3 60.5 50 -4168.96 428.0 181.6 Min = -25400Max = -23450Range = 1949.99 V-Nominal Frequency Int. Time Time Delay 50 kHz 10 sec 3000 200 Program: STABHV - 12 Minute Test DC Stan. Dev. Stan. Dev. Stan. Dev. No. of Mean (PPM) Observation Mean Mean *3 Readings 10.0 0.0 0.0 0.0 10 Max = 9.99451 Range = 0Min = 9.99451AC No. of Stan. Dev. Stan. Dev. Stan. Dev. Mean (PPM) Observation Mean Mean *3 Readings 137.2 411.6 -3890.0 433.9 10 Max = -23600Range = 1149.98 Min = -24750Int. Time Time Delay V-Nominal Frequency 5 10 sec 200 50 kHz

3) Manually set the TE comparator to its "high TE" voltage input position, and switch the voltmeter to its 10-mV range. The program automatically closes the dc voltage relay and a-low-thermal-noise switch (K2) turns on the dc standard and triggers the voltmeter to obtain the TE voltage output reading.

4) Switch the TE comparator to its "low TE" voltage input position. The program then triggers the voltmeter to read the voltage. The values of the high- (from the previous step) and low-voltage readings are compared. If the latter is actually larger in magnitude than the former, the operator is instructed to interchange the two TE inputs after the dc voltage has been turned off. The program automatically stores the correct value of E-low, since that value is used in the equation to determine the ac/dc difference of the test unit (see section 2.2).

5) Switch the TE comparator to the "high TE" voltage input position. This step in the procedure is done only if the test unit actually has a greater emf output than the standard. If not, the comparator switch remains in the "low TE" voltage input position. In either event, the operator is then instructed to turn on the Lindeck potentiometer, change the voltmeter to its $10 \ \mu$ V range, and manually adjust the potentiometer until the voltmeter indicates about 500 nV.

6) Switch K2 is opened, and a second low-thermal noise-switch (K1) is closed. The operator now manually adjusts the Kelvin-Varley divider until the voltmeter indicates a voltage within the range ±100 nV.

7) Switch Kl is opened, K2 closed, the ac voltage relay is closed, the ac standard turned on, and its voltage is automatically incremented or decremented until the output voltage of the UUT's TE is $\leq 1 \mu V$ of its value with dc voltage applied, as in step 6.

8) At this point, the manual initialization process is complete, switch K2 is opened, Kl is closed, and the test proceeds automatically under program control. A sequence of voltage readings is obtained by the voltmeter when ac, dc+, dc-, and ac voltages are applied to the standard thermal voltage converter and UUT. These four voltage readings are each obtained from the average of ten readings of the voltmeter. The standard deviation of the ten readings is computed, and if this value is < 200 nV, the program continues. If the standard deviation is \geq 200 nV, due to drifts in either the standard converter or the UUT, or the ac or dc standards, or any of these effects combined, the series of ten readings is repeated. After five attempts, if the voltmeter readings have not stabilized, the test is aborted.

9) The sequence of readings with ac, dc+, dc-, and ac voltages applied constitutes one determination of the ac/dc correction to the UUT. The process is continued for four determinations; the average value of four determinations is computed and printed. The operator then may elect to repeat the test, change voltage range or frequency, or stop the test. A sample of data printed on the teletypewriter is illustrated in table 5. Although only low-voltge test results are shown, the data format is identical for high-voltage tests.

			able 5. A					
			•••••					
			•••••					
	APP		STANDARD	ES	ET	NSEL		
	V 30.0	RANGE 50.0	TE RANGE FD 100.	MV 0 4.5	MV 3.3	N*MV 6.40		
kHz	COR	50.0	AC/DC DIF		5.5	0.40	STD	AVE T
KI12	PPM		10,00 011	. EIVENGE			DEV	COR PPM
50.0 50.00	-2 -2		(273 27 (275 28		277) 289)		3.2 4.9	275.3 277.5
	30.0	50.0	FD 100.	0 4.5	3.2	6.38		
kHz	COR PPM		AC/DC DIF	FERENCE			STD DEV	AVE T COR PPM
20.00	0		(100 12		100)		9.7	106.4
20.00 20.00	0 0		(102 10 (97 10		117) 105)		7.6 7.0	107.6 105.7
	50.0	50.0	FD 100.	0 11.2	8.4	14.92		
kHz	COR PPM		AC/DC DIF	FERENCE			STD DEV	AVE T COR PPM
50.00	-2		(278 28		279)		1.1	277.1
50.00 50.00	-2 -2		(280 28) (285 28)		281) 286)		1.0 2.7	277.7 279.4
	50.0	50.0	FD 100.	0 11.2	8.4	14.92		
kHz	COR PPM		AC/DC DIF	FERENCE			STD DEV	AVE T COR PPM
20.00	0		(106 10		105)		1.6	106.4
20.00	0	50.0	(107 10		106)	14 00	1.4	106.0
611-	50.0	50.0	FD 100.		8.4	14.92	CTD	AVE T
kHz	COR PPM		AC/DC DIF	FERENCE			STD DEV	AVE T COR PPM
10.00	0		(51 5		52)		0.5	51.5
10.00 10.00	0 0		$\begin{pmatrix} 35 & 34 \\ 43 & 4 \end{pmatrix}$		33) 41)		10.1 8.1	42.2 42.1
10.00	0		(39 4		43)		7.0	42.1
	50.0	50.0	FD 100.		8.4	14.92		
kHz	COR PPM		AC/DC DIF	FERENCE			STD DEV	AVE T COR PPM
5.00 5.00	0 0		(19 2 (20 1	1 19 9 20	18) 18)		1.5 1.1	19.4 19.3
NUMBER	OF REA	DINGS=H	{=	64				
NUMBER	OF IND	DEP. TES	STS=L=	ó				
A STIELIN								

DEGREES OF FREEDOM=D1=.....58

POOLED ESTIMATE OF TEST STD.DEV. OF MEAN=S2 =S.D.T. (SEE S.P. 300,V.1, P. 316-40)....=1.02083

3. MEASUREMENT RESULTS AND UNCERTAINTIES

There are many factors which contribute to the uncertainty of ac/dc difference measurements of the type described in this report. Similar manual systems have been in operation for many years at NBS and their uncertainties have been documented [1-3]. DC reversal difference of a TE, self-heating and ambient temperature effects, drift effects due to non-equal time intervals during the voltage measurements, unbalanced lead impedances, and induced voltages from electromagnetic fields are some of the more common factors. The process of determining an estimated total uncertainty for a system is based upon experience with the system, careful measurements of standards with accurately known corrections, or intercomparison tests of two independent test methods [3]. The latter procedure, involving comparison of a well-characterized manual system with the new one, was followed, since the uncertainty sources are believed to be similar in both systems.

The system performance was verified by an extensive testing procedure which involved the use of a multi-range thermal voltage converter instrument as a transport standard. The transport standard was first tested for ac/dc differences at various combinations of applied voltages and frequencies using the MIDAS-based system. It was then tested, at similar voltages and frequencies with the same standard thermal voltage converters, using the manual testing technique which has been used for many years at NBS. A third test was performed, again using the MIDAS system. Finally, the MIDAS system was disassembled, physically relocated, reassembled, and tested for proper operation. Then the transport standard was tested a fourth time, again using the MIDAS system. It should be noted that not all voltage range-frequency combinations were tested for all four tests. However, in those cases where fewer than four tests were performed, the results indicated sufficiently small differences between at least two independent test methods to establish that further testing was not warranted. The results of these independent intercomparison tests are listed in table 6, and the range of ac/dc differences is listed in table 7. In evaluating these results, it must be remembered that, for calibrating multirange instruments like the transport standard, the manual test system has uncertainties of the same magnitude as the semiautomatic system. Hence, combined total uncertainties of the order of 100 and 200 ppm are possible depending upon the test frequency.

In table 7, the column listing "Voltage Range" refers to the input voltage range of the transport standard, the "Test Voltage" is the actual test voltage applied, and the different columns for frequency are the actual test frequencies used. The numbers listed under the frequency columns are the maximum differences (in ppm) of the calibrated ac/dc difference corrections for the transport standard as determined for at least two, and up to a maximum of four, of the test conditions described above. That is, the numbers reported are the range (magnitude of the maximum minus the minimum) of the ac/dc difference corrections measured for each test voltage and frequency. The total elapsed time between the first and final tests of the transport standard was about eight weeks. Table 6. Transport standard ac/dc differences (ppm)

	No. 4	120.9	ł	ł	ł	;	ł	ł	6.1	112.5	-43.5	-748.7	ł	1
kHz	No. 3	132.5	101.1	1	ł	ł	2.8	-3.9	ł	ł	;	ł	ł	ł
100 1	No. 2	137.01	98.0 1	16.0	15.0	8.0	0	-12.0	-6.0	116.0	-58.0	-788.0	1227.0	1
	No. 1	144.3	101.6	25.4	15.2	4.6	6.1	-2.9	-3.6	103.8	-43.7	-754.0	1080.2	;
	No. 4	93.4	ł	ł	ł	ł	ł	1	6.1	37.6	-0-6	-386.7	239.2	26.6
50 kHz	No. 3	102.9	71.9	ł	ł	ł	5.2	2.9	ł	ł	ł	ł	ł	ł
50	No. 2	112.0	74.0	24.0	14.0	4.0	-1.0	3.0	4.0	38.0	1.0	-443.0	235.0	97.0
	No. 1	106.3	71.8	17.5	13.6	4.6	14.0	12.5	3.0	32.5	0.4	-387.6	184.7	ł
	No. 4	49.2	1	ł	ł	1	ł	-	5.6	19.1	4.8	3.1	43.0	-25.8
20 kHz	No. 3	57.4	36.4	ł	1	ł	1.6	10.7	!	ł	ł	ł	ł	ł
20	No. 2	67.0	45.0	11.0	6.0	7.0	1.0	3.0	4.0	20.0	8.0	5.0	29.0	-9*0
	No. 1	58.4	36.9	12.2	7.8	7.0	9.0	5.9	2.8	18.1	8.5	6.8	20.5	1
IIZ	No. 2	ł	1	ł	ł	ł	7.0	ł	1	ł	;	ł	ł	!
20 Hz	No. 1	;	ļ	5	ł	ł	21.8	ł	;	ł	ł	ł	ł	ł
Applied	voltage volts	0.5		2	3	8	16	30	50	98	200	500	500	1 000
	Range	.25 - 0.5	0.5 - 1	1 - 2	2 - 4	4 - 8	8 - 16	16 - 32	32 - 64	64 - 125	125 - 250	250 - 500	500 - 1000	500 - 1000

No. 1 - Automatic System

No. 2 - Old Manual System #2, Rm. A144

No. 3 - Repeat Automatic System

No. 4 - Automatic System, Rm. A144

Voltage range	Test voltage (volts	<u>2</u>	Test Frequer 0 50	<u>ncy (kHz)</u> <u>100</u>
0.25-0.5	0.5	1	8 19	23
0.5 - 1	1	9	9 2	4
1 - 2	2		1 6	9
2 - 4	3		2 0	0
4 - 8	8		0 1	- 3
8 - 16	16		8 15	3
16 - 32	30		8 10	9
32 - 64	50		3 3	10
64 - 125	98		2 6	12
125 - 250	200		4 2	14
250 - 500	500		4 50	39
500 - 1000	500	2	2 54	147
500 - 1000	1000	1	7 70	

Table 7. Range of ac/dc differences for transport standard (Ppm)

The test results show that at 20 kHz the average value of the range of ac/dc differences for all voltages is only 8 ppm. At 50 kHz the average value of the range is 19 ppm, and at 100 kHz, where skin effects and stray capacitance effects predominate, the largest range (at 500 V) was 147 ppm. However, this large range is within the expected combined total uncertainty of 200 ppm for the two systems. Even with this one range greater than 100 ppm, the average value of the range at 100 kHz is still only 23 ppm. No intercomparison results were obtained at 1000 V, 100 kHz, since the high-voltage-amplifiers in both systems could not supply sufficient power at that voltage-frequency combination.

Additional intercomparison tests were made using a single-range, coaxial type thermal voltage converter with large, but accurately known, ac/dc differences. The summary of the test results is shown in table 8. From the data, it is obvious that the two systems agreed well within the estimated total uncertainty limits. In fact, the data clearly show that the MIDAS-based system performed much better than had been anticipated when the project was undertaken.

As a final check of the system's performance, intercomparison tests were made using a single-range, coaxial type converter, which is used as a working standard for ac/dc testing at NBS. The results of these tests are summarized in table 9. Again, the results indicate excellent agreement between the two systems.

4. CONCLUSIONS AND RECOMMENDATIONS

The results of the work reported indicate that it is possible to measure ac/dc differences semiautomatically with uncertainties about the same as those obtained with manual testing techniques. The major advantage of the system appears to be the elimination of most of the tedium involved in manual testing, in which deflections of light beam galvanometers must be observed and recorded.

For future work, it appears that further improvements in system operation can be obtained by development of self-balancing TE comparators. Additionally, by taking advantage of improvements in digital voltmeter sensitivity, stability, linearity, and resolution, desktop computers, and system components whose operation is compatible with new digital/analog interfaces, it may be possible to develop improved ac/dc difference testing techniques.

5. ACKNOWLEDGEMENTS

The authors are indebted to C. B. Childers who made many of the tests, assembled the equipment, and helped the programmers test the software. E. S. Williams designed and built the low-thermal-noise and high-voltage switching modules, and provided some of the initial software which eventually became part of the total programming package. R. E. Kleimann, S. C. Bailey, and W. C. Caterisano each contributed portions to some of the computer programs. Thanks are also due B. A. Bell who provided helpful comments, encouragement, and support.

System											
l Applied voltage	2 Frequency kHz	3 Manual	4 MIDAS	3-4 Difference							
50	5	24	22	2							
50	10	52	50	2							
50	20	116	113	3							
50	50	308	305	3							

Table 8. AC/DC difference for TVC "FA 50" (ppm)

Table 9. AC/DC difference for TVC "FC 100" (ppm)

	1	Sys	tem			
l Applied voltage	2 Frequency kHz	3 Manual	4 MIDAS	3-4 Difference		
100	20	3	5	-2		
100	50	3	4	-1		
100	100	13	18	-5		

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APPENDIX A

Hardware

Equipment lists, parts lists, and wiring diagrams of the equipment used in the NBS Semiautomatic AC/DC Thermal Voltage Converter Calibration System are contained in this appendix.

The use of trade names or company products does not constitute endorsement or recommendation by the National Bureau of Standards, and does not imply that the products named are necessarily the best available for the purpose.

- 1. List of Equipment.
 - 1. Data Precision Model 5740 Frequency Meter.
 - 2. Fluke Model 3330B Programmable DC Voltage Standard.
 - 3. Hewlett-Packard Model 745A AC Voltage Standard, option H18.
 - 4. Hewlett-Packard 746A High Voltage Amplifier.
 - 5. Leeds & Northrup Model 9829D Digital Linear Amplifier.
 - 6. Guildline Model 9577 Digital Voltmeter with BCD interface.
 - 7. Data Precision Model 175 Digital Multimeter (2 ea).
- 2. Parts list for High Voltage Switching Module.
 - 1. D1-D4: IN5620 diodes.
 - 2. T1: Rectifier transformer. Universal Rectifier Corp., model RT201.
 - K1-K4: Relays. Magnecraft Electric Co., model W158HVX1, SPDT, DB-DM, 24 VDC. Rated 200 mA coil, 5 kV dc, 120 Ω coil.
 - 4. S1, S2: CTS Rotary switch, series 212, #T205.
 - 5. Pl: Cable connector. Gen-Rad, type GR874-CA.
 - 6. J1: Panel connector. Gen-Rad, type GR874-PBA.

¹For the frequency output connector of the ac calibrator, a triax BNC to regular BNC adaptor is required. The adaptor used was made by Trompeter Electronics, part number AD-PL76-E1-B120.

- 7. Pilot light. Industrial Devices, 215 OA1.
- 8. J2-J4. BNC male panel mount connectors isolated from panel.
- 9. All resistors 1/4 W.
- 3. Parts list for Low-Thermal-Noise Switching Module.
 - K1-K5: Solenoids. Guardian Electric Co., pull type #24DC. Coil voltage 24 V dc. 114 Ω coil resistance.
 - 2. Jl: Panel jack. Amphenol #3102A receptacle, #10S-02P insert.
 - 3. Pl: Cable plug. Amphenol #3106B connector, #10S-02P insert. #AN3057 cable clamp.
 - 4. J2-J9: BNC male panel mount connectors isolated from panel.
 - 5. P2: Cable plug. Amphenol #3106B plug, #14S-05 insert, #AN3057-6 cable clamp.
 - 6. S1: C.T.S. rotary switch, series 212, #T205.
 - 7. All L.E.D.'s red, 5V, 16 mA.

4. Parts list for TE Comparator.

Jl & J2: Panel jack. Amphenol #3102A receptacle, #10S-02P insert.

J3: Panel jack. Amphenol #3102A receptacle, #14S-05P insert.

J4: Panel jack. Amphenol #3102A receptacle, #10SL-03P insert.

Battery: Mallory Duracell RM42R 1.35 V.

Meter: 0-1 mA, DC.

R1, R2: 10 Ω Gen-Rad #602-302.

R3: Beckman Helipot #SA 4391, 10 turn, 100 Ω , ±3%. (Lindeck potentiometer fine adjust).

R4: 750 Ω , 10%, 1/2 W, carbon.

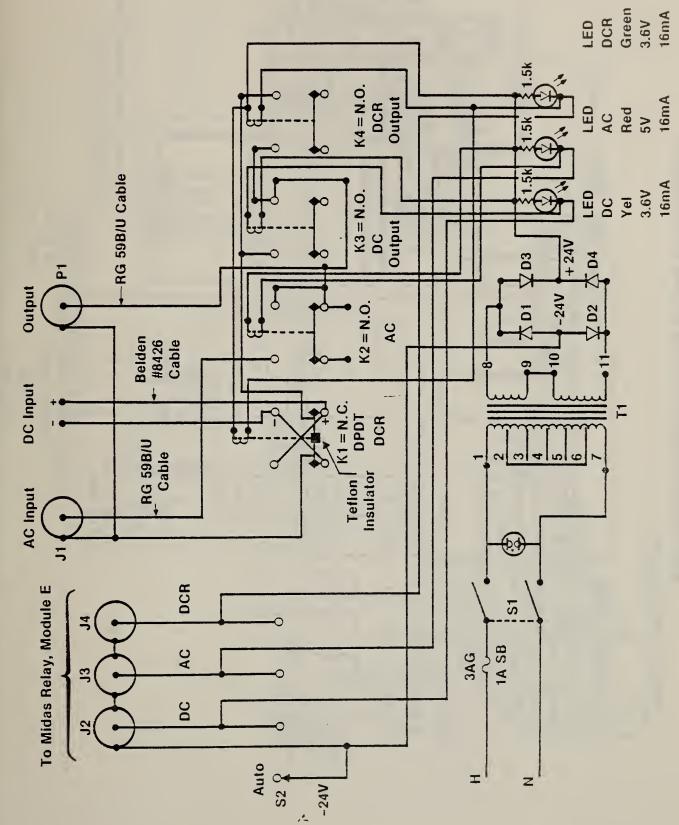
R5: Beckman Helipot #SA4912, 10 turn, 100 Ω , $\pm 3\%$.

R6, R7: 100Ω , $\pm 10\%$, 1/2 W carbon.

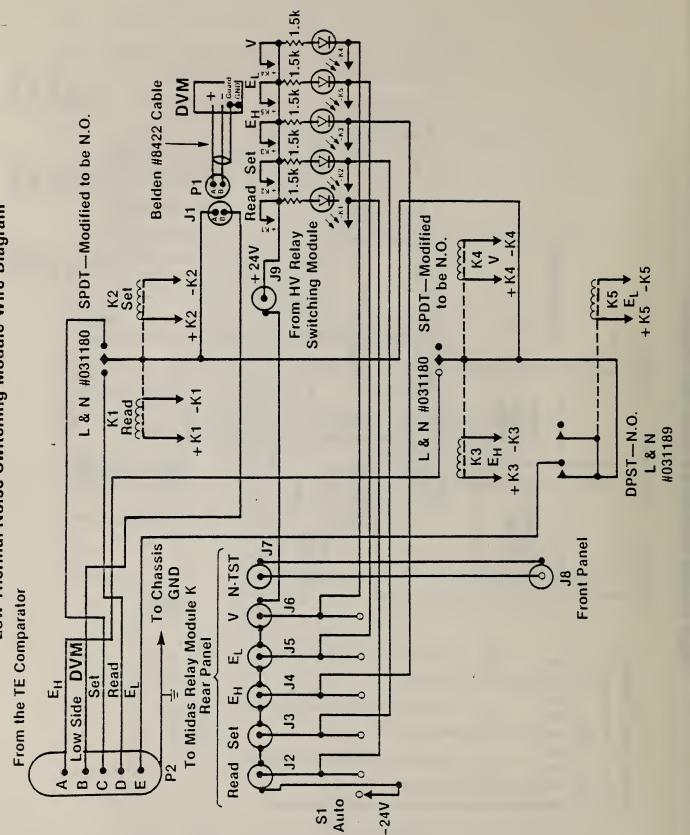
R8, R9: $53k \Omega$, $\pm 10\%$, 1/4 W, carbon.

R10, R11: 1_{Ω} , $\pm 1/2\%$, 1 W, precision pie wound.

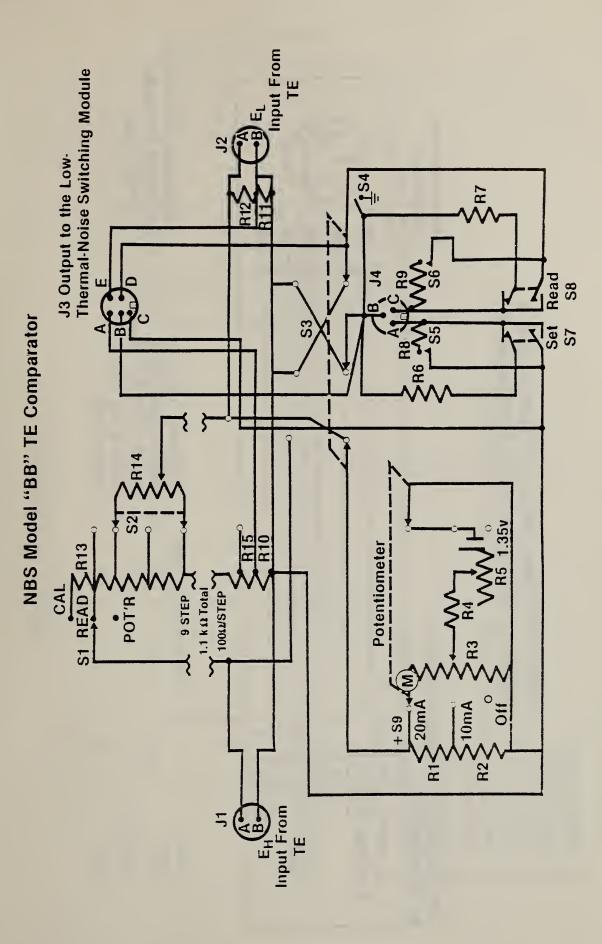
- R12: Precision pie wound, $lk \Omega$, $\pm 1/2\%$, 1 W.
- R13: Precision pie wound, 0.05Ω , $\pm 1/2\%$, 1 W.
- Rl4: Beckman Helipot #SA5427, 10 turn, 100Ω , $\pm 3\%$. (Kelvin-Varley divider fine adjustment).
- R15: Gen-Rad #602-303, 100 Ω.
- S1: Leeds & Northrup 12 position, 2 pole rotary selector switch #031262. (Function switch).
- S2: Leeds & Northrup 12 position, 3 pole rotary selector switch #031263. (Kelvin-Varley divider coarse adjust).
- S3: Leeds & Northrup 12 position, 6 pole rotary selector switch #031266. (E-high or E-low selector switch).
- S4: SPST bat handle toggle switch.
- S5, S6: Set and read detector sensitivity switches. Leeds & Northrup SPST #031187.
- S7, S8: Set and read switches. Leeds & Northrup Guarded Low Thermal Key switch DPST #031189.
- S9: C.T.S. 7 position 2 pole rotary switch, series 212, #T205. (Lindeck potentiometer coarse adjust).



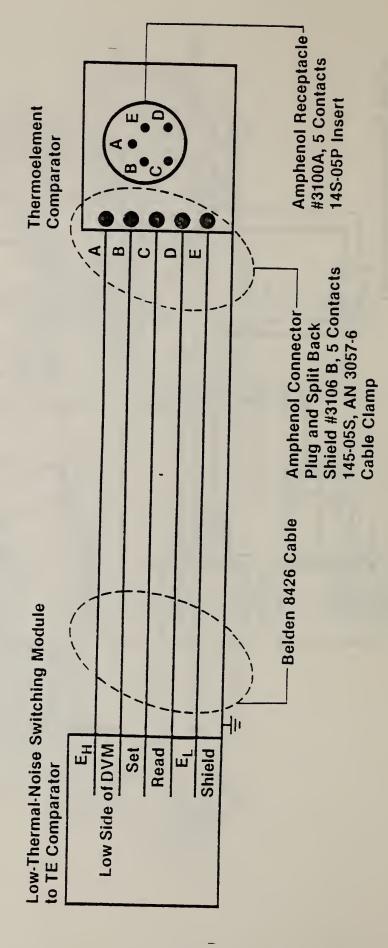
High Voltage Switching Module Wire Dlagram



Low-Thermal-Noise Switching Module Wire Diagram







Midas Equipment List

			œ
24	A	System Controller	M70-010
23	8	BCD I/O	M70-190
22	c	BCD Reg.	M70-140
21	D	BCD Reg.	M70-190 M70-190 M70-030 M70-040 M70-140 M70-140 M70-190 M70-010B
20	ш	Relay	M70-040
19	Ŀ	BCD Multi- plexer	M70-030
18	ច	BCD	M70-190
17	H	BCD	M70-190
		Vacant	
11	х	Relay	M70-040
Slot #	Midas Add.	Midas Power Supply	Model M70-200A

Slot #

- 10 Midas Power Supply
- Relay, Low-Thermal-Noise Switch, V = 1, EL = 2, EH = 3 Set = 4, Read = 5, NTSTF = 6 From Top Down E
- BCD I/O, Guildline 17
- BCD I/O, Dana 18
- **BCD Multiplexer** 19
- Relay, High Voltage Switch, DCR= 1, AC=2, DC=3 From Top Down 20
- **BCD Reg., Fluke DC Voltage** 21
 - BCD Reg., H.P. AC Voltage 22
- BCD I/O, DVM
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APPENDIX B

ACDCHV Detailed Program Description and Program Listing

For ease of understanding the following detailed narrative program description, the reader may find it useful to refer to the list of program variables on page 40, and the program listing on page 44. Although not included in this report, a detailed program flow chart is available upon request.

The program begins by describing the software and appropriate reentry points, as well as system limitations which would result in over-voltages. Lines 20-108 are print statements which display the descriptive information and warnings on the CRT. Statement 109, in which the program shunts around a variable index (lines 110-1020) and a data header (lines 1030-1170), is inserted when debugging, and deleted for formal testing when a heading is desired on the printed data sheet. In statements 1180-1280, string and array variables are dimensioned, and simple variables are initialized. The statements in lines 1290-1310 generate, through a read command and a series of data statements (lines 1320-1400), a library containing corrections to those TE standards that might be used during an ac/dc difference test.

The constants stored in data lines 1320-1390 are those which are used to calculate the value of the standard TE's dimensionless characteristic "n." Since n varies with applied voltage, its value can be related to the TE's measured emf output, E (in mV). The value of n is assumed to vary linearly with E. Thus, for example, for the standard "F1" in line 1320, n is calculated as

n = 1.98 - 0.039E.

String variables used for instructions to MIDAS are then dimensioned and defined (lines 1400-1420). Since instructions from, and data sent to, MIDAS are done in real time, delay statements are used to handle timing intervals between reception of programmed instructions and acquisition of data. An upper limit for these delay statements is defined in statement 1430 concluding the system's software initialization.

A series of linked subroutines comprise the body of the program which actually begins at line 1440. A print command causes the CRT to beep, prompting the operator to enter, via the CRT keyboard, a test voltage, test range, and standard TE range after a request for such test requirements has been displayed (line 1450). A conditional statement in line 1470 tests the status of flag S. S is set to 1 after an initial test so that for any succeeding tests, the program jumps to subroutines which turn off both dc and ac voltages, restoring each set of test parameters when required (lines 5970-6050 for dc, and 6060-6160 for ac). During a first run, however, S equals zero so the program falls through, first to set the dc voltage, then to set the ac.

Both voltage-setting routines follow similar general formats. Statements in lines 3430-3990 set the ac voltage, while statements 4640-5190 set the dc. Before requesting voltage, range, and frequency (ac only) parameters, instructions for coding these parameters are displayed on the CRT. Any variables which may yet be necessary are then established. These include temporary variables (such as F18, R18, and V28 in ac, and R2 and V18 in dc), all of which are used to store parameters when turning supplies on and off during high voltage tests. Any flags for branching around certain instructions when testing at high voltages are also included here; for example, D in the ac routine (lines 3620-3650). Because the initial instructions to MIDAS differ, depending on a preselected range, conditional statements determine program flow to one of several sets of separate commands. Each of these command sets issues an initial instruction to MIDAS for a particular range before going back to the voltage set subroutine for more generalized instructions which send, through MIDAS, previously defined parameters. After MIDAS has sent the commands to those instruments being programmed, the operator is prompted, via the CRT, to check if each device has actually responded correctly. Should the operator indicate that a response is incorrect, the program recycles the subroutine to receive new instructions. If operator response indicates that the instruments have responded correctly, control is returned to statement 1520 of the main program.

After both dc (1500) and ac (1510) voltages have been set, instructions are displayed telling the operator to select the E-high comparator input, turn off the Lindeck potentiometer and the ground switch of the comparator and set the voltmeter to its 10 mV range. A variable for the test number is incremented, while both "dc" and a low-thermal-noise (K2) relay are closed. The operation of the high voltage relays, as well as those solenoids contained in the low-thermal-noise switch module, is accomplished by instructions contained in repeatedly-accessed subroutines in lines 5690-5900. Next, the dc power supply is turned on to the previously programmed voltage value (1610). Before the voltmeter is read (1640), the program executes a time delay (1620-1630) to permit the TE to reach thermal equilibrium. Statements 1641-1651 ask which standard TE is being used and check through a data library for its correction. This correction is used in each of two formulas, only one of which is accessed, contingent upon whether the standard or the UUT is connected to the E-high or E-low input of the comparator (1750-1770).

When $E_s > E_t$ the program variable K is computed as

$$K = E_{t}n_{s} = E_{t} (M_{s} - N_{s}E_{s}),$$

and, when $E_t > E_s$, K is computed as

$$\langle = E_{s}n_{s} = E_{s} (M_{s} - N_{s}E_{s}),$$

where the subscripts t or s refer to the UUT or the standard TE, respectively, and M and N are constants as defined in the program

variable list on page 40. These equations have been derived in [2]. The emf of the TE connected to the E-high input is read first by the voltmeter, and its value displayed on the CRT. Should E-low have a greater emf output than the TE connected to the comparator's E-high input, the operator is instructed to switch comparator connections, the test is aborted (1655-1718), and the initialization process begun again. If the standard and test TE's are properly connected to the comparator, K is computed and printed on the data sheet along with voltage, test range, standard TE range, and emf outputs for both the standard and the UUT.

If the UUT's emf actually is E-high, the operator is prompted to select the E-high input of the TE comparator (if E-test < E-high, the input selector switch remains at the E-low position). The potentiometer is turned on, the 10 μ V range of the voltmeter selected, and the potentiometer adjusted until the voltmeter indicates within ±500 nV. Instructions and prompts in the statements in lines 1830-1950 cue the operator to execute these manual operations. Then relay K2 opens and relay K1 closes (lines 1970-1990). The operator is then instructed to adjust the Kelvin-Varley voltage divider (±100 nV), after which dc voltage parameters are stored, and the dc standard turned off. Both "dc" and K1 relays open now, while relay K2 closes. Column headings for the data sheet are printed, and variables for statistical calculation are initialized.

Appropriate frequency corrections are computed for the standard TE. Statements 2220-2230 prompt the operator to define the test frequency, and statements 2240-2320 use this frequency value to determine the correction and truncate the computed correction to a whole number. Now the "dc" relay closes, and the dc power supply is turned on to the previously selected test voltage, at which point the K2 relay closes. The operator is then directed to readjust the potentiometer, after which the dc voltage and range values are stored, the power supply turned off, and the "dc" relay opened. Then the "ac" relay closes and the ac power supply is turned on, first at 105 volts and finally to the proper high voltage. A time delay in lines 2480-2490 allows the ac supply to settle and the TE to reach thermal equilibrium before transferring control to an ac voltage check subroutine (4000-4630) that adjusts the ac voltage so that the output of the test TE is within 1000 nanovolts of its output with dc voltage applied. The subroutine branches, depending upon whether the ac voltage is too high or too low. The ac voltage is adjusted to provide nominally equal UUT output only with direct dc voltage applied, and not when reversed dc is applied. Furthermore, this ac voltage adjustment is made only once at the beginning of the measurement sequence to obtain four determinations of ac/dc difference. Hence, it is possible, for UUT's with large dc reversal differences, for second-order errors to become significant. However, the multirange instrument and single range thermal converters tested with this system did not possess large dc reversal differences.

The system was intended to calibrate high-quality thermal converters. Hence, additional balancing steps to eliminate uncertainties due to large dc reversal difference (i.e., difference between the dc direct and reverse voltages required for the same TE emf output of the UUT) were not needed. For the worst case, using 2.0 and 1.6 as the two extremes of the characteristic n which may occur for the standard and UUT TE's, it can be shown [4] that systematic uncertainties of less than one-fourth the UUT's dc reversal difference will occur. Minor software changes can eliminate this systematic error if large reversal voltages are anticipated. The changes would amount to adjusting the ac voltage for a TE output equal to that when dc reversed voltage is applied to the test circuit. The only penalty for such a change in the operating procedure would be an increase in testing time of perhaps one or two minutes (for four determinations of ac/dc difference).

There is also the possibility of a systematic uncertainty if the ac or dc voltage standards drift during a sequence of four determinations. However, for the same extremes of n, the uncertainty is only 10 ppm if either source drifts by as much as 100 ppm. The STABLV and STABHV programs readily provide information about the stabilities of the sources.

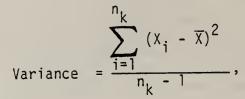
Once the ac voltage has been adjusted for about equal TE output as when dc is applied, relay K2 opens and relay K1 closes (2510-2540). Cautions are displayed on the CRT to allow the voltmeter to stop drifting before rebalancing the divider, should that be necessary. Statements in lines 2600-2610 generate a time delay before the program jumps to test the 10 voltmeter readings (5500-5650) to determine if the standard deviation of an observation of 10 readings is < 200 nV. The test routine allows for up to five reading sequences to be obtained before the test is aborted and a suitable warning displayed on the CRT.

AC/DC difference is reported on the basis of the average of four determinations. Each determination is calculated from the voltage measurements with ac, dc+, dc-, and ac voltages applied simultaneously in this sequence to the standard and test TE's. The last ac reading of one determination becomes the first ac reading of the next determination. Each reading is taken by closing the appropriate relays, bringing up the power supplies to previously programmed values, displaying the reading in nanovolts, then storing the voltage parameters, powering down, and opening the relays. This measurement process is accomplished by means of statements in lines 2650-3050 and concludes the midsection of the program.

The final section of the program computes statistical parameters, formats the final output, generates a copy of the test data, and provides measurement options to the operator. Statements 3060-3130 calculate the mean of the four determinations and the standard deviation of an observation in ppm, while statements 3140-3150 format the printed data, and the statement in line 3160 causes the data to be printed. Should the operator wish to run another test, variables used to determine a pooled standard deviation are then incremented in lines 3170-3230. Finally, options are displayed (3240-3250) asking whether to repeat a test with or without averaging, to change parameters, or to terminate. Since ac was the last measurement to be taken, its voltage is turned off, although the ac parameters are automatically stored for potential reruns (3275). Statements 3280-3350 transfer program control to the operator-selected option. If the operator has chosen to repeat a test without averaging, lines 3380-3410 delete the pooled standard deviation data.

The standard deviation of an observation printed on the data sheet is calculated for the four determinations of ac/dc difference at a fixed voltage and frequency from the following:

 $(Standard deviation)^2 = (Variance), and the$



where, $\overline{X} = \frac{i=1}{n_k}$, and n_k is the number of determinations at a fixed

voltage and frequency; i.e., the number of readings in test $k = n_k$.

The final statistics which are printed on the data sheet are calculated using the variables

- H = total number of readings,
- L = Number of independent tests,
- D1 = Degrees of freedom = H-L,
- S2 = Pooled estimate of the test standard deviation of the mean = standard deviation of the test (SDT).

An estimate of the total random uncertainty is calculated as three times the SDT and this product is therefore an estimate of the average 3σ value for the test, and is calculated as

$$3\sigma = 3 \left\{ \frac{\sum_{k=1}^{t} \left[\sum_{i=1}^{n_{k}} (X_{i} - \overline{X})^{2} \right]}{(n-t) (n/t)} \right\}^{1/2}$$

where, the degrees of freedom = n-t,
total number of readings = n =
$$\sum_{k=1}^{t} n_k$$

number of independent tests = t.

These concepts are discussed fully in [9], pp. 316, ff.

ACDCHV PROGRAM VARIABLES

Note: Ø = zero and not letter "oh"				
Variable Name	Definition			
А	Voltage applied to test and standard TE.			
AÓ	Array used to store the four determinations of ac/dc difference.			
A2	Variable in the subroutine used to increase or decrease the ac voltage when driving the UUT's output to within 1000 nV of its value with dc voltage applied.			
A4	Variable which is input by the operator after verifying the dc voltage (Ø or 1).			
A5	Variable which is input by the operator after verifying the ac voltage and frequency (0 or 1).			
A6	Variable which is input by the operator after determining whether or not to change the frequency after the ac voltage is set.			
В	Voltage range of test TE.			
BØ	Average of all determinations at one voltage and frequency.			
81	Average of the four latest determinations of the test. Bl is used in the computation of the standard deviation of the test.			
В\$	Array used to store the data related to a particular TE.			
С	Frequency correction to standard TE which is calculated by using test frequency (P).			
C7	Variable used to increment or decrement the ac voltage to drive the UUT's output to within 1000 nV of its value with direct dc applied.			
C\$	String containing name of standard TE.			
CØ\$	Variable used in input string to dc source to set range, polarity, remote trip, and voltage trip range.			
D	Flag to initially turn on ac supply at 105 V, and then return and set the correct voltage and range.			
DI	Variable used for degrees of freedom in statistical calculations. D1 = H-L.			
D\$	String used to input date.			

Variable	
Name	Definition
Ε	E-high voltage reading, in mV.
E9	E-low voltage reading, in mV.
E1-E4	DLA voltage difference readings with ac, +dc, -dc, and ac voltages applied to the standard and UUT TE's.
FØ\$	Used to input frequency to the ac source.
F1\$	Storage variable for the ac source frequency used in the ac voltage setting routine.
G	Dummy variable.
н	Total number of determinations of ac/dc difference per test run.
Ι	Variable defining a for/next loop in which the standard TE code file is established.
IØ	Variable used to designate the first element in array A (the test voltage) when defining the variables M and N. Also used to define El = near-null voltage reading with ac applied, E2 = reading with +dc, E3 = reading with -dc, E4 = reading with ac.
I\$	String used to input the test instrument manufacturer, name, and model number.
18	Variable used to define the for/next time interval loop.
19	Variable used to define the for/next "wait" timing loop; e.g., to allow the dc or ac supplies to settle, or to allow time for a TE to reach thermal equilibrium.
J	Flag for abort and total reset.
JI	Variable used to define for/next loop in which X6 is computed. Jl is used in the pooled estimate of the test standard deviation of the mean.
K	Result of the standard TE's emf multiplied by the TE characteristic $n_{\rm S}$ when ${\rm E_S}$ $<$ ${\rm E_t},$ or the test TE's emf times $n_{\rm S}$ when ${\rm E_S}$ $>$ ${\rm E_t}.$
KØ	Variable used to define a for/next loop in which the ten DLA near-null voltage readings are obtained, and then calculate the standard deviation of the ten readings.

Variable Name	Definition		
L	Number of independent tests for a complete test run; i.e., for all voltages and frequencies.		
М	One of two constants used in the calculation of n _s . The other constant is N.		
MØ	Variable used to implement MIDAS calls. MØ is the computer's PASLA channel number in decimal.		
R1	Variable used to set the range of the dc supply.		
R2\$	Variable used to store the range of the dc supply before turning it off.		
RØ\$	Variable used to select the range for the ac supply.		
R\$	Character string reference used for relay operation.		
R1\$	Variable used to store the range of the ac supply before turning it off.		
S	Flag for initial dc and ac voltage ranges.		
S1	Standard deviation of an observation for four or more determinations of ac/dc difference at one voltage and frequency.		
S2	Pooled estimate of the test standard deviation of the mean.		
Т	Decision point variable.		
ТØ	Time delay variable.		
Т\$	Output format string.		
۷\$	MIDAS input string.		
V0\$	String used to set voltages on both ac and dc supplies.		
V1 \$	Variable used to store the dc voltage value in the dc voltage setting routine.		
V2\$	Variable used to store the ac voltage value in the ac voltage setting routine.		
٧	Numeric value of V\$. V is the value of the voltage reading.		

Variable Name	Definition
W	Divisor used in the calculation of the mean of four or more determinations at one voltage and frequency.
X,X1,X2	All used in the standard deviation of the test (SDT). calculation.
X5,X6,X7	Used in calculating the pooled estimate of the standard deviation of the mean.
Y	Intermediate variable used in calculating Y1.
Y1	Standard deviation of ten voltmeter readings.
Z	Counter in the five standard deviation abort subroutine.

```
20 ;"PROG. NAME=ACDCHV"
30 ;"PROG. TESTS AC-DC DIFF. AT HI V(>100V;RANGE=1000)"
40 ;" PROGRAM CONTAINS SUBROUTINE(S) FOR TURNING ON 4 OFF"
50 ;" HI.V. AMP. (AC) & FLUKE (DC, DCR) WHEN SWITCHING RELAYS."
60 ;" THIS PROGRAM HAS AUTOMATIC CONTINGENCY FOR TURNING ON HI.V.AMP."
70 J" INITIALLY AT 105 VOLTS."
80 ;" PROG. CAN BE USED AT BOTH LO. & HI. VOLTAGES."
90 J" TO RESET, RUN 5910."
95 J" TO MAKE DECISION(S) AFTER INITIAL RUN, RUN 3240."
96 3
97 3
98 ;"
                     CAUTION"
100 ;" READ THIS CAREFULLY!"
101 ;" FLUKE ALWAYS USES 1KV RANGE! HENCE, FOR LO VOLTAGE TESTS"
102 J" TO PREVENT DC OVERVOLTAGE, USE PRECEEDING ZEROES FOR CORRECT V"
103 J"EG- 9V ON 1 KV RANGE=0090000, AND 90V ON 1 KV RANGE=0900000"
104 ; MAKE SURE HP HI-VOLT. AMP. IS ON"
105 J"TIME DELAY TO SET IN LINE 1430"
106 3
107 3
108 ;
109 GOTO 1180
110 REM INDEX
111 REM THIS PROG. USES THE FOLLOWING VARIABLES
112 REM A,A0,A2,A4,A5,B,B0,B1,B$,C,C7,C$,C0$,
113 REM D, D1, D5, E, E1, E2, E3, E4, E9, F05, F15, G, H,
114 REM 1,10,18,19,15,J,J1,K,K0,L,M,M0,M1,M2,
115 REM NJNSJOJOSJO2SJPJP0JRJR0JR1JR2JRSJR0SJR1SJ
116 REM SJSIJSZJTJTOJTSJVJVSJVOSJVISJVZSJWJ
117 REM X,X1,X2,X5,X6,X7,Y,Y1,Z
120 REM PRG. LINES 110-1020: PROGRAM INDEX & DEF. OF VARIABLES
130 REM 1030-1170: TEST DATA HEADING PRINTOUT
140 REM 1180-1460: INITIALIZATION OF DATA
145 REM
             1470: CONDITIONAL FOR RANGE CHANGE
              1480: CALL TO DC VOLTAGE SET SUB.
150 REM
160 REM
              1490: CALL TO AC VOLTAGE SET SUB.
170 REM 1530-2320: EH & EL READINGS & VARIABLE INPUTS
180 REM 2330-2570: AC VOLTAGE APPLIED
190 REM 2590-3050: AC-DC-DCR READINGS
195 REM 2940-2950: SAFETY MEAS. - CLOSE READ IN CASE OPEN
200 REM 3060-3230: DATA PRINT & STATIS. CALCS.
210 REM 3240-3410: END OF TEST DECISION POINT
220 REM 3420-3990: AC VOLTAGE SET ROUTINE
224 REM
              3600: INITIAL STORAGE OF AC FREQUENCY
226 REM 3730-3740: INITIAL STORAGE OF AC PARAMETERS
230 REM 4000-4630: AC CHECK ROUTINE (DRIVES AC WITHIN
240 REM
                    100 NANOVOLTS OF DC)
```

241 REM NOTE: TO CHANGE NULL RANGE - LINE 4080 243 REM TO CHANGE INCREMENT - LINES 4150 & 4400 FOR L.V. FOR H.V. INCREMENT - LINES 4170 & 4420 250 REM 4640-5190: DC VOLTAGE SET ROUTINE 255 REM 4760-4770: INITIAL STORAGE OF DC PARAMETERS 260 REM 5200-5390: STATIS. PRINT ROUTINE FOR POOLED S.D. 270 REM 5400-5490: DLA READ ROUTINE 280 REM 5500-5680: STD. DEV. TEST (OF DLA READINGS) 290 REM 5690-5790: E-MOD. RELAY SET ROUTINE (HI. V. SW.) 300 REM 5800-5900: K-MOD. RELAY SET ROUTINE (LO. THER. SW.) 310 REM 5910-6640: RESET; TURN-OFF & TURN-ON SUBROUTINE 312 REM 5950-6050: TURN-OFF FLUKE & REDEFINE DC PARAM. 314 REM 6060-6160: TURN-OFF HI.V.AMP. & REDEFINE AC FARAM. 316 REM 6170-6330: TURN-ON FLUKE & RESTORE DC PARAM. 318 REM 6340-6630: TURN-ON HI.V.AMP. & RESTORE DC PARAM. 320 REM RUN 3360: TO CHANGE RANGE 320REMRON33601110 CHANGERANGE330REM1510:TOCHANGEFREQUENCY340REM2330:TOREPEAT TEST350REM3290:TORESETRELAYS360REM3380:TOTOREPEAT W/O360REM3380:TOTOREPEAT W/O370REM5200:TOGETPOOLED380REM5910:TOABORT & RESETALLREM5910:TOABORT & RESETALLREM5910:TOADDITO 390 REM A=VOLTAGE APPLIED TO STANDARD TE. 400 REM A0=ARRAY USED TO STORE THE 4 DETERMINATIONS. 410 REM A2=INCREMENTED IN AC VOLTAGE CHECK ROUTINE 420 REM B=RANGE OF TEST TE 430 REM B0=AVE. OF ALL RDGS. OF A PARTICULAR TEST. 440 REM BI=AVE. OF ONLY 4 LATEST READINGS. 450 REM BS=ARRAY USED TO STORE EACH TE'S CONSTANTS. 460 REM C=STD. TE FREQ. CORR. DETERMINED FROM INPUT FREQ=P 470 REM C7=VOLTAGE INCREMENT IN AC BALANCE ROUT. 480 REM CS=STRING CONTAINING I.D. OF STD. TE 490 REM COS=USED IN INPUT STRING TO DC SOURCE 500 REM D=COUNTER FOR INITIAL INPUT (105 V) FOR HI.V.AMP.(AC) 510 REM DI=DEGREES OF FREEDOM=H-L 520 REM DS=STRING USED TO INPUT DATE 530 REM E=E-HIGH MILLIVOLT READING (EH) 540 REM E9=E-LOW MILLIVOLT READING (EL) 550 REM E1 TO E4=ALTERNATING AC-DC-DCR-AC NULL READINGS 560 REM FOS=USED TO INPUT FREQ. TO AC SOURCE 570 REM G=DUMMY VARIABLE 580 REM H=TOTAL NO. OF DETERMINATIONS PER RUN 590 REM IS=STRING USED TO INPUT TEST INSTRUMENT MFG. & MODEL NO. 600 REM J=COUNTER FOR ABORT & TOTAL RESET 610 REM K=PRODUCT RESULT OF STD. EMF*STD. 612 REM TE CHARACTERISTIC (N, LOWER CASE) 614 REM WHEN ES<ET 616 REM OR TEST EMF*STD TE CHARACTERISTIC 618 REM (N, LOWER CASE) WHEN ES>ET 620 REM L=TOTAL NO. OF TESTS PER RUN 630 REM M=CONSTANT USED TO DETERMINE STD. TE 631 REM CHARACTERISTIC N-SUBSCRIPT S (N. LOWER CASE) 640 REM MO=IN MIDAS CALL IS THE PASLA CHANNEL NO. IN DEC. 650 REM M1=MAX. LENGTH OR TERMINATING CHAR. 651 REM OF MIDAS INPUT STRING 660 REM M2=STATUS VARIABLE SET AFTER 661 REM EACH MIDAS CALL

680 REM NS=STRING USED TO INPUT OPERATOR'S NAME 690 REM OS=INPUT STRING SPECIFYING PHYSICAL ADDRESS 700 REM 025=STRING USED TO INPUT TEST NO. 710 REM P=FREQUENCY INPUT (KHZ) 720 REM R=RANGE OF STD. TE 730 REM RO=VARIABLE SELECTS RELAY OPERATION 740 REM HV RELAYS. E-MODULE. R0=1..CLOSE DCR RELAY 750 REM RO=2..CLOSE AC RELAY 760 REM RO=3. CLOSE DC RELAY 770 REM RO=11. OPEN DCR RELAY 780 REM RO=12. OPEN AC RELAY 790 REM RO=13. OPEN DC RELAY 800 REM X-MODULE. R0=3, CLOSE EH. R0=2, CLOSE EL RELAY. 810 REM RO=4..CLOSE SET RELAY 820 REM RO=5. CLOSE READ RELAY 830 REM RO=13; OPEN EH. RO=12; OPEN EL RELAY. 840 REM RO=14. OPEN SET RELAY 850 REM RO=15. OPEN READ RELAY 860 REM RO=0. OPEN ALL RELAYS 870 REM ROS=RANGE SELECT FOR AC SOURCE 880 REM RS=CHARACTER STRING REFERENCE USED FOR RELAY OPERATION 890 REM S=COUNTER FOR RANGE 900 REM SI=STD. DEV. OF AN OBS. FOR 901 REM 4 OR MORE DETERMINATIONS 910 REM S2=POOLED EST. OF TEST S.D. OF MEAN 920 REM T=DECISION POINT VARIABLE 920 REM T=DECISION POINT VARIABLE 930 REM T0=TIME DELAY LOOP VARIABLE 940 REM TS=OUTPUT FORMAT 950 REM VS=STRING OUTPUT FROM MIDAS 960 REM V0S=STRING INPUT TO SET VOLTAGE 961 REM ON BOTH AC 4 DC SOURCES 970 REM V=NUMERIC VALUE OF VS 980 REM V=DIVISOR IN AVE. CALC. 990 REM X,X1,X2,X5,X6,X7=ALL USED IN S.D.T. 1000 REM Y=USED IN Y1 CALC. 1000 REM Y=USED IN Y1 CALC. 1010 REM Y1=STD. DEV. OF 10 DLA READINGS 1020 REM Z=COUNTER OF Y1'S Z=5=ABORT 1030 DIM 02\$(6), I\$(20), D\$(15), N\$(25) 1040 J"INPUT CURRENT DATE, YOUR NAME, TEST NO. , AND TEST INST." -1050 1* 1060 INPUT DS.NS.025.IS 1080 J ON (6) 1090 J ON (6) DBSERVER...... = JNS 1100 J ON (6) 1120 J ON (6) 1140 J ON (6) 1150 J DN (6) 1160 J ON (6)"APPTESTSTANDARDESETX"1170 J ON (6)"VRANGETERANGEMVMV" 1180 DIM F0\$(2),F1\$(2),R0\$(1),R1\$(1),V0\$(7),V1\$(7),V2\$(7) 1190 DIM COS(3),CS(2),TS(72),BS(7,8),A(8,2)

```
1200 S=0
1210 J=0
1220 D=0
1230 M0 = 38
1240 Z=0
1250 H=0
1260 L=0
1270 X7=0
1280 ¥=0
1290 FOR I=1 TO 8
1300 READ BS(1),A(1,1),A(1,2)
1310 NEXT 1
1320 DATA "F1",1.98,.39E-1
1330 DATA "F2",2:03,:28E-1
1340 DATA "FG",2:04,31E-1
1350 DATA "FC", 1.9, .32E-1
1360 DATA "FH",2:02; 32E-1
1370 DATA "FA",2:03,:42E-1
1380 DATA "FB", 1.94, 14E-1
1390 DATA "FD",2:03,:42E-1
1400 DIM VS(12), OS(29), RS(16)
1410 VS="
1420 RS="776>5=4<3;2:1908"
1430 T0 = 1800
1440 3*
         .
1450 ;"INPUT TEST VOLTAGE, TEST RANGE, STD. RANGE" .
1460 INPUT A.B.R
1470 IF S=0 GOTO 1500
1480 GOSUB 5970
1490 GOSUB 6060
1500 GOSUB 4640
1510 GOSUB 3420
1520 ;*
1530 J"SET COMP. TO E-HIGH, POT'R OFF, DLA 10 MV, GND OFF"
1540 J"TO CONTINUE, RETURN"
1550 INPUT G
1560 L=L+1
1570 R0=3
1580 GOSUB 5690
1590 R0=4
1600 GOSUB 5800
1610 GOSUB 6170
1620 FOR 19=1 TO 1600
1630 NEXT 19
1640 GOSUB 5400
1641 J INPUT THE CODE FOR STANDARD 'TE' (IN QUOTES)"
1642 ;* -
1643 INPUT CS
1644 FOR I=1 TO 8
1645 IF BS(I) <> CS THEN 1648
1646 ID=I
1647 I=100
1648 NEXT I
1649 IF I>=100 THEN 1653
1650 J"STANDARD NOT FOUNDJ TRY AGAIN"
1651 ;- -
```

```
1652 GOTO 1641
1653 M=A(10,1)
1654 N=A(10,2)
1655 E=V#1000
1660 J"E-HIGH
               -",E, "MILLIVOLTS"
1670 J"CHANGE 'BB' TO E-LOW, THEN RETURN
1680 INPUT G
1690 GOSUB 5400
1700 E9=V#1000
             =",E9,"MILLIVOLTS"
1710 J"E-LOV
1712 IF E>E9 THEN 1720
1714 3*
1716 ;"E-LOW IS GREATER THAN E-HIGH, SWITCH CONNECTIONS"
1718 GOTO 5910
....
                                ....
                                              ....
                                                     ....
                                    ....
1730 J ON (6)
1740 3 - -
1750 J"IF"JCSJ"IS E-HIGH, INPUT '1'. IF NOT, INPUT '0'."
1760 INPUT G
1770 IF G=0 GOTO 1810
1780 K=E9*(M-E*N)
1790 J ON (6) USING TSJAJBJCSJRJEJE9JK
1800 GOTO 1940
1810 K=E9*(M-E9*N)
1820 J ON (6) USING TS,A,B,CS,R,E9,E,K
1830 3" "
1840 J"SET COMPARATOR TO E-HIGH. RETURN"
1850 INPUT G
1940 J"POT'R ON - SET DLA 10 MICRO-VOLTS - SET NULL, RETURN"
1950 3 .
1960 INPUT G
1970 R0=14
1980 GOSUB 5800
1990 R0=5
2000 GOSUB 5800
2010 J"BALANCE DIVIDER, THEN RETURN"
2020 3"
2030 INPUT G
2035 GOSUB 5970
2040 R0=15
2050 GOSUB 5800
2060 R0=13
2070 GOSUB 5690
2080 R0=4
2090 GOSUB 5800
2110 ; ON (6)
2120 ; ON (6)" KHZ
                                        AC-DC DIFFERENCE
                        COR
2130 ; ON (6)" STD
                       AVE T"
2140 J ON (6)*
                        PPM
                     COR PPM"
2150 J ON
         (6)"DEV
2160 J ON (6)
2170 X=0
2180 \times 1 = 0
2190 X2=0
2200 C=0
2210 V=0
```

- ,

```
2220 J INPUT FREQUENCY (KHZ)"
2230 3
           .
2240 INPUT P
2250 IF R<100 THEN C=0
2260 IF R=100 THEN C=-(P<sup>2</sup>/1000)
2270 IF R=200 THEN C=-(P<sup>2</sup>/1000)
2280 IF R=300 THEN C=(P<sup>2</sup>/1000)<sup>1.5</sup>
2290 IF R=600 THEN C=(P<sup>2</sup>/1000)<sup>1</sup>.3
2300 IF R=1001 THEN C=(P<sup>2</sup>/100)*2-P
2310 IF R=1002 THEN C=P<sup>2*</sup>.12E-1
2320 C=INT(C)
2330 R0=3
2340 T=3
2350 GOSUB 5690
2360 GOSUB 6170
2370 ;*
2380 R0 = 4
2390 GOSUB 5800
2400 J" SET POT NULL, THEN RETURN"
2410 INPUT G
2420 GOSUB 5970
2430 R0=13
2440 GOSUB 5690
2445 GOSUB 6060
2450 R0=2
2460 GOSUB 5690
2470 GOSUB 6340
2480 FOR 19=1 TO 2000
2490 NEXT 19
2500 GOSUB 4000
2510 R0=14
2520 GOSUB 5800
2530 R0=5
2540 GOSUB 5800
2550 IF W<>0 THEN 2600
2560 ; WAIT FOR DLA TO STOP DRIFT.
2570 ; "REBALANCE DIVIDER IF NECESSARY, THEN RETURN."
2580 ;* *
2590 INPUT G
2600 FOR 19=1 TO TO
2610 NEXT 19
2620 GDSUB 5500
2630 E1=V*.1E10
2640 ;"El
                    =",E1, "NANOVOLTS"
2650 FOR I0=1 TO 4
2660 GOSUB 6060
2670 R0=12
2680 GOSUB 5690
2690 R0 = 3
2700 GDSUB 5690
2710 GOSUB 6170
2720 FOR 19=1 TO TO
2730 NEXT 19
2740 GOSUB 5500
2750 E2=V*.1E10
```

2760 J E2 =",E2, "NANOVOLTS" 2770 GOSUB 5970 2780 R0=13 2790 GOSUB 5690 2800 R0=1 2810 GOSUB 5690 2820 GOSUB 6170 2830 FOR 19=1 TO TO 2840 NEXT 19 2850 GOSUB 5500 2860 E3=V*.1E10 =",E3, "NANOVOLTS" 2870 ;"E3 2880 GOSUB 5970 2890 R0=11 2900 GOSUB 5690 2910 R0=2 2920 GOSUB 5690 2930 GOSUB 6340 2940 R0=5 2950 GOSUB 5800 2960 FOR 19=1 TO TO 2970 NEXT 19 2980 GOSUB 5500 2990 E4=V#.1E10 3000 J"E4 =",E4, "NANOVOLTS" 3010 A0(I0)=(-E1+E2+E3-E4)/(2*K) 3020 IF 10=4 THEN 3050 3030 E1=E4 3040 ;"E1 =",E1, "NANOVOLTS" 3050 NEXT 10 3060 W=W+4 3070 X=X+A0(1)²+A0(2)²+A0(3)²+A0(4)² 3080 X1=X1+A0(1)+A0(2)+A0(3)+A0(4) 3090 B1=A0(1)+A0(2)+A0(3)+A0(4) 3100 B1=B1/4 3110 B0=X1/₩ 3115 P0=(X1/W)+(C) 3120 X2=B0*X1 3130 S1=SQR((X-X2)/(W-1)) 3140 T\$(1,50)="####. -## 3160 J ON (6) USING T\$;P;C;A0(1);A0(2);A0(3);A0(4);S1;P0 3170 H=H+4 3180 X6=0 3190 FOR J1=1 TO 4 3200 X5=(A0(J1)-B1) 2 3210 X6=X6+X5 3220 NEXT J1 3230 X7=X7+X6 3240 ; "REPEAT, FREQUENCY, RANGE, STOP, REPEAT W/O AVE. ?" 3250 3 2 3 5 1 4 3260 3-. 3270 INPUT T 3275 GOSUB 6060 3280 IF T=4 THEN 5200_

```
3290 M1=0
3300 OS="<35>E89: J<=>?K89: J<=>?"
3310 CALL 1,M0,05,V5,M1,M2
3320 IF T=1 THEN 2330
3330 IF T=2 THEN 1510
3340 IF T=3 THEN 3360
3350 IF T=5 THEN 3380
3360 S=1
3370 GOTO 1450
3380 X7=X7-X6
3390 H=H-4
3400 ; ON (6) "ABOVE DATA DELETED FROM TEST"
3410 GOTO 2160
3420 GOSUB 6060
3430 3
3440 ;"
                           AC VOLTAGE SET
3460 ; "WHEN SETTING AN AC VOLTAGE OF 1,10,0R 100 VOLTS, YOU MUST"
3470 J"CHOOSE THE MAX. OUTPUT OF THE CORRESPONDING RANGE, FOR EXAMPLE"
3480 ; "WHEN APPLYING 10 V YOU MUST PROGRAM 5-NINES (99999) ON THE 10 V"
3490 ; "RANGE, AND NOT (REPEAT NOT) 10000 ON THE 100 V RANGE"
3500 1
3510 J
3520 ;"THE FREQUENCY IS CODED IN TWO DIGITS. THE FIRST DIGIT MUST BE"
3530 ;"A NUMBER FROM 1 TO 11, MEANING THE HIGH ORDER DIGIT. THE"
3540 ;"SECOND DIGIT ARE MULTIPLES OF 10, STARTING WITH 0=X10 AND"
3550 ;"3 = X10 K. IN HEX- A TEN IS A': AND A ELEVEN IS A'; "
3560 ;
3570 ;*
3580 ;"INPUT FREQUENCY"
3590 INPUT FOS
3600 F1S=F0S
3610 3
3620 D=1
3630 R05="6"
3640 GOSUB 6420
3650 D=0
3660 ; TO SET VOLTAGE AND RANGE, FIRST INPUT THE CORRECT RANGE"
3670 ; FOLLOWED BY THE 5-DIGIT VOLTAGE. A RANGE OF 0 = 1MV, 1 = 10MV,
3680 \ s^2 = 100 \text{MV}, 3 = 1 \text{V}, 4 = 10 \text{V}, 5 = 100 \text{V}, and 6 = 1000 \text{V}.
3682 J" WHEN TEST LO & HI AC MUST SET RANGE TO NEXT"
3684 ;" HIGHEST RANGE LIMIT FROM TEST VOLTAGE"
3686 ;" (EX. 1 - TEST 4 V AC SET RANGE AT 4=10V OR"
3688 ;" EX. 2 - TEST 100 V AC SET RANGE AT 6=1000)."
3690 ;
3700 ;*
       -
3710 J"INPUT RANGE, VOLTAGE'
3720 INPUT ROS, VOS
3730 R1S=R0S
3740 V25=V05
3750 IF R05="6" GOTO 3820
3760 DS="<35>CP"+V0S(1,5)+R0S+F0S+"02"
3770 CALL 1, M0, 05, VS, M1, M2
3780 M1=1
3790 OS="<35>F8"
```

3800 CALL 1, M0, OS, VS, M1, M2 3810 GOTO 3880 3820 OS="<35>CP"+V0S(1,5)+R0S+F0S+"20" 3830 J 3840 J"CONNECT HIGH VOLTAGE AMP., THEN RETURN" 3850 ;* * 3860 INPUT G 3870 GOTO 3770 3880 J"CHECK AC VOLTAGE AND FREQUENCY, IF CORRECT INPUT '1'," 3890 J"THEN RETURN. IF INCORRECT, INPUT '2' , THEN RETURN." 3900 3 . 3910 INPUT A5 3920 IF A5=1 GOTO 3940 3930 GOTO 3420 3940 J"IF FREQ. CHANGE INPUT '1', IF RANGE OR INITIAL RUN, RETURN' 3950 3" 3960 INPUT A6 3970 IF A6=1 GOTO 2160 3980 IF R05="6" GOTO 6060 3990 RETURN 4000 J"AC VOLTAGE CHECK" 4010 R0=2 4020 GOSUB 5690 4030 GOSUB 5400 4040 JV 4050 A2=V 4060 A2=A2*.1E9 4070 V=V#+1E9 4080 IF ABS(A2)<100 THEN 4600 4090 IF VS(1,1)="-" THEN 4350 4100 IF R05="4" THEN 4140 4110 IF R05="5" THEN 4140 4120 IF ROS="6" THEN 4140] 4130 GOTO 4150 4140 IF VOS(1,1)="9" THEN 4170 4150 C7=3 4160 GOTO 4180 4170 C7=40 4180 A2=VAL(V0\$) 4190 A2=A2-C7 4200 V05=STRS (A2) 4210 M1=0 4220 IF R05="6" GOTO 4290 4238 DS="<35>CP"+V0S(1,5)+R0S+F0S+"02" 4240 CALL 1, M0, 05, V5, M1, M2 4250 M1=1 4260 0\$="<35>F0" 4270 CALL 1,M0,05,V5,M1,M2 4280 GOTO 4310 4290 OS="<35>CP"+V0S(1,5)+R0S+F0S+"20" 4300 GOTO 4270 ... 4310 FOR 18=1 TO 1500 4320 NEXT 18 4330 GOSUB 5400 4340 GOTO 4040

4350 IF R05="4" THEN 4390 4360 IF R05="5" THEN 4390 4370 IF R05="6" THEN 4390 4380 GOTO 4400 4390 IF VOS(1,1)="9" THEN 4420 4400 C7=3 4410 GOTO 4430 4420 C7=40 4430 A2=VAL(V05) 4440 A2=A2+C7 4450 V05=STRS (A2) 4460 M1=04470 IF R05="6" GOTO 4540 4480 OS="<35>CP"+V0S(1,5)+R0S+F0S+"02" 4490 CALL 1, MO, OS, VS, MI, M2 4500 M1=1 4510 OS="<35>F0" 4520 CALL 1,M0,05,V5,M1,M2 4530 GOTO 4560 4540 OS="<35>CP"+V0S(1,5)+R0S+F0S+"20" 4550 GOTO 4520 4560 FOR 18=1 TO 1500 4570 NEXT 18 4580 GOSUB 5400 4590 GOTO 4040 4600 R0=2 4610 V=V/.1E9 4620 GOSUB 5690 4630 RETURN DC VOLTAGE SET 4640 J 4650 VS=" 4660 ; 4670 J"TO SET THE VOLTAGE RANGE AND TRIP, INPUT FIRST THE CORRECT" 4680 J"RANGE FOLLOWED BY A COMMA AND THE DESIRED VOLTAGE. RANGES" 4690 JOF 10, 100, AND 1000 ARE ALLOWED. VOLTAGE MUST BE 7 DIGITS." 4695 J" WHEN TEST AT LO V (<=100 V DC) MUST SET RANGE AT 1000." 4700 3 4710 J" INPUT RANGE, VOLTAGE" 3. 4720 4730 M0=38 4740 M1=0 4750 INPUT RI,VOS 4760 R2=R1 4770 V15=V05 4780 IF R1=10 GOTO 4990 4790 IF R1=100 GOTO 5030 4800 IF R1=1000 GOTO 5070 4810 GOTO 4710 4820 OS="<35>DP"+V0S+"JJ"+C0S 4830 CALL 1, M0, 05, VS, M1, M2 4840 M1=1 4850 OS="<35>F0" 4860 CALL 1, M0, 05, V5, M1, M2 4870 V\$ (2,2)=" " 4880 JVS

4890 IF VAL(VS) <> 6 THEN 5110 4900 J"CHECK DC VOLTAGE, IF CORRECT INPUT "1", THEN RETURN." 4910 J'IF INCORRECT, INPUT'2', THEN RETURN" 4920 3 -4930 INPUT A4 4940 IF A4=1 GOTO 4950 4945 IF A4=2 GOTO 5130 4950 GOTO 5970 4960 RETURN 4970 GOTO 4640 4980 RETURN 4990 COS="840" 5000 OS="<35>DP000000033"+C0S 5010 CALL 1, M0, 05, VS, M1, M2 5020 GOTO 4820 5030 COS="942" 5050 CALL 1, M0, 05, V5, M1, M2 5060 GOTO 4820 5070 COS="=41" 5080 OS="<35>DP0000000;;"+COS 5090 CALL 1, M0, OS, VS, M1, M2 5100 GOTO 4820 5110 J"WARNING - SYSTEM TRIPPED, SUPPLY AUTOMATICALLY RESET" 5120 J" TRY AGAIN." 5130 M1=0 5140 V0\$="0000000" 5150 COS="000" 5160 OS="<35>DP"+V0S+"00"+C0S 5170 CALL 1, M0, 05, VS, M1, M2 5180 GOTO 4640 5190 RETURN 5200 J"DO YOU WANT STATISTICS PRINTOUT?" 5210 J"IF YES, ENTER '1' AND RETURN" 5220 J"IF NOT ,ENTER '2' AND RETURN" -5230 3* 5240 INPUT T 5250 IF T=2 THEN 5910 5260 D1=H-L 5270 S2=SQR((X7/D1)/(H/L)) 5280 J ON (6) 5300 J ON (6) (6) "NUMBER OF INDEP. TESTS=L=...,L 5310 J ON 5320 J ON (6) 5340 J ON (6) (6) POOLED ESTIMATE OF TEST STD. DEV. OF MEAN=S2" 5350 J ON (6) = S. D. T. (SEE S. P. 300, V.1, P. 316-40)= ,52 5360 J ON 5370 ; ON (6) 5380 ; ON (6) 3*5. D. T. =.... 3*52 5390 GOTO 5910 ···· 5400 M1=12 5410 OS="<35>BTTU<17>"

```
5420 CALL 1,M0,05,V5,M1,M2
5430 VS(LEN(VS)+1, LEN(VS)+1)=" "
5440 IF VS(2,2)=":" THEN 5480
5450 IF VS(2,2)=":" THEN 5480
5460 V=VAL(VS)
5470 RETURN
5480 V=2000
5490 RETURN
5500
    Y=0
5510 Y1=0
5520 FOR K0=1 TO 10
5530 GOSUB 5400
5540 Y=Y+V
5550 Y1=Y1+V*V
5560 NEXT KO
5570 Y1 = SQR((Y1 - (Y^*Y/10))/9)
5580 IF Y1*.1E10<200 THEN 5660
5590 ; STD. DEV. = , Y1*.1E10, NANOVOLTS"
    Z=Z+1
5600
5610 IF Z=5 THEN 5630
5620
    GOTO 5500
    J"WARNING-JOB ABORTED, TESTS EQUAL FIVE, SYSTEM UNSTABLE"
5630
     3*
5640
       .
5650
     GOTO 5910
5660 V=Y/10
5670
    Z=0
5680 RETURN
5690 R0=INT(R0)
    IF R0>=0 AND R0<19 THEN 5730
5700
    J" INVALID RELAY ADDRESS"
5710
5720 RETURN
5730 M1=0
5740 R1=INT(R0/10)
5750 R2=INT(R0-R1*10)
5760 IF R0<>0 THEN 05="<35>E"+R$(2*R2-1+R1,2*R2-1+R1)
5770
    IF R0=0 THEN 0$="<35>E89:;<=>?"
5780 CALL 1, M0, 0$, V$, M1, M2
5790 RETURN
5800 R0=INT(R0)
    IF R0>=0 AND R0<19 THEN 5840
5810
5820
    ;"INVALID RELAY ADDRESS"
5830 RETURN
5840 M1=0
5850 R1=INT(R0/10)
5860 R2=INT(R0-R1*10)
5870 IF R0<>0 THEN 0$="<35>K"+R$(2*R2-1+R1,2*R2-1+R1)
5880 IF R0=0 THEN OS="<35>K89:;<=>?"
5890 CALL 1, M0, OS, VS, M1, M2
5900 RETURN
5910 R0=0
5940
    J=1
5950 R0=0
5960 Z=0
5970 M1=0
```

5980 V0\$="0000000" 5990 COS="000" 6000 OS="<35>DP"+V0S+"00"+C0S 6010 CALL 1, M0, 05, V5, M1, M2 6020 IF J=1 GOTO 6080 6030 V0S=V1S 6040 R1=R2 6050 RETURN 6060 M1=06070 V0S="0000000" 6080 R05="0" 6090 F05="00" 6100 OS="<35>CP"+V0S(1,5)+R0S+F0S+"00" 6110 CALL 1,M0,OS,VS,M1,M2 6114 GOSUB 5690 6120 IF J=1 GOTO 6640 6130 R05=R15 6140 V05=V25 6150 F0S=F1S 6160 RETURN 6170 M0 = 386180 M1=0 6190 COS="=41" 6200 OS="<35>DP0000000JJ"+C0\$ 6210 CALL 1, M0, 05, V5, M1, M2 6220 V05=V15 6230 R1=R2 6240 FOR 19=1 TO 100 6250 NEXT 19 6260 OS="<35>DP"+V0S+";;"+C0S 6270 CALL 1,M0,05,V5,M1,M2 6280 M1=1 6290 OS="<35>F0" 6300 CALL 1,M0,05,V5,M1,M2 6310 R2=R1 6320 V15=V05 6330 RETURN 6340 M1=0 6350 V0\$="0000000" 6360 R05="0" 6370 F05="00" 6380 OS="<35>CP"+VOS(1,5)+ROS+FOS+"00" 6390 CALL 1,M0,OS,VS,M1,M2 6400 R05=R15 6410 F05=F15 6420 VOS="10500" 6430 FOR 19=1 TO 100 6440 NEXT 19 6450 OS="<35>CP"+V0\$(1,5)+R0\$+F0\$+"20" 6460 CALL 1,M0,OS,VS,M1,M2 6470 M1=1 6480 OS="<35>F0" 6490 CALL 1,M0,0\$,V\$,M1,M2

```
6500 FOR 19=1 TO 150
6510 NEXT 19
6520 M1=0
6530 IF D=1 GOTO 6630
6540 V05=V25
6550 OS="<35>CP"+VOS(1,5)+ROS+FOS+"20"
6560 CALL 1,M0,OS,VS,M1,M2
6570 M1=1
6580 OS="<35>F0"
6590 CALL 1,M0,05,V5,M1,M2
6600 F15=F05
6610 R1S=R0S
6620 V25=V05
6630 RETURN
6640 GOSUB 5800
6650 END
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described to 100 kH all volta the total for volta addition adapted t calibrato the new s a multira The resul within th	miautomatic ac/dc differe The system operates ov z, covering the voltage r ges at frequencies in the uncertainty is 50 parts ges at frequencies betwee to ac/dc difference testi to calibrate precision ac ors. Results of extensive system against a manual te nge thermal transfer inst ts indicate that the ac/d e combined total uncertai	er a frequency rai ange from 0.5 V to range from 20 Hz per million (ppm) n 20 kHz and 100 H ng, the system can digital voltmeter intercomparison to st system are report rument as a transp c differences mean nty limits of the	nge of 20 Hz o 1 kV. For to 20 kHz, , and 100 pp kHz. In be readily s or ac testing of orted, using bort standar sured are we two systems	om
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